Computer Architecture

Lecture 10: Low-Latency Memory

Prof. Onur Mutlu
ETH Zürich
Fall 2020
22 October 2020

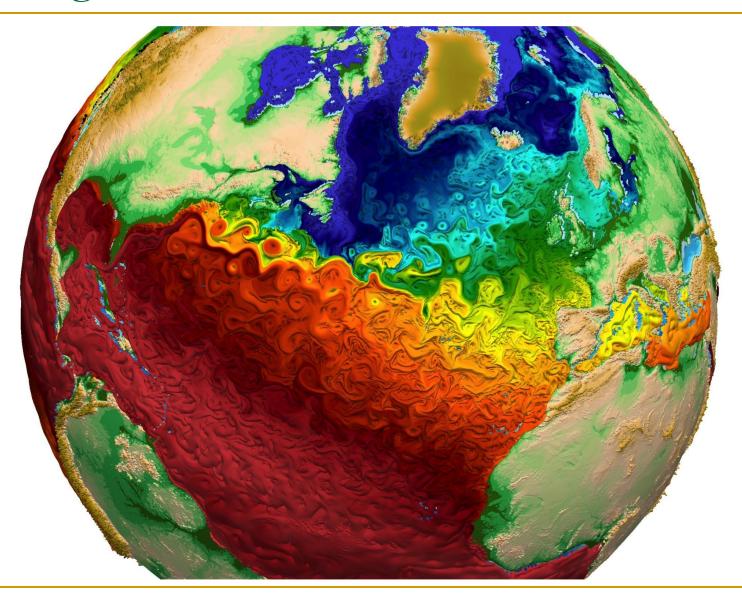
Four Key Directions

Fundamentally Secure/Reliable/Safe Architectures

- Fundamentally Energy-Efficient Architectures
 - Memory-centric (Data-centric) Architectures

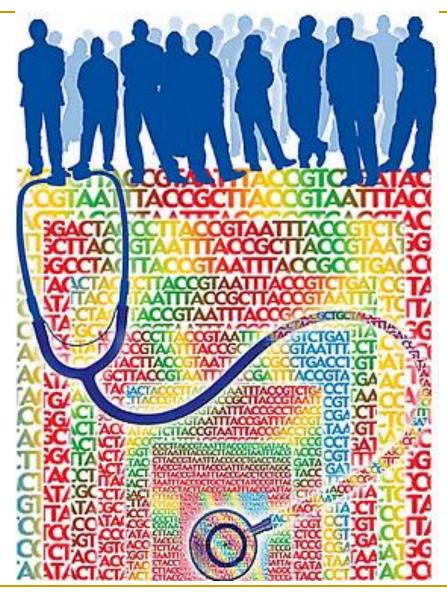
Fundamentally Low-Latency Architectures

Architectures for Genomics, Medicine, Health



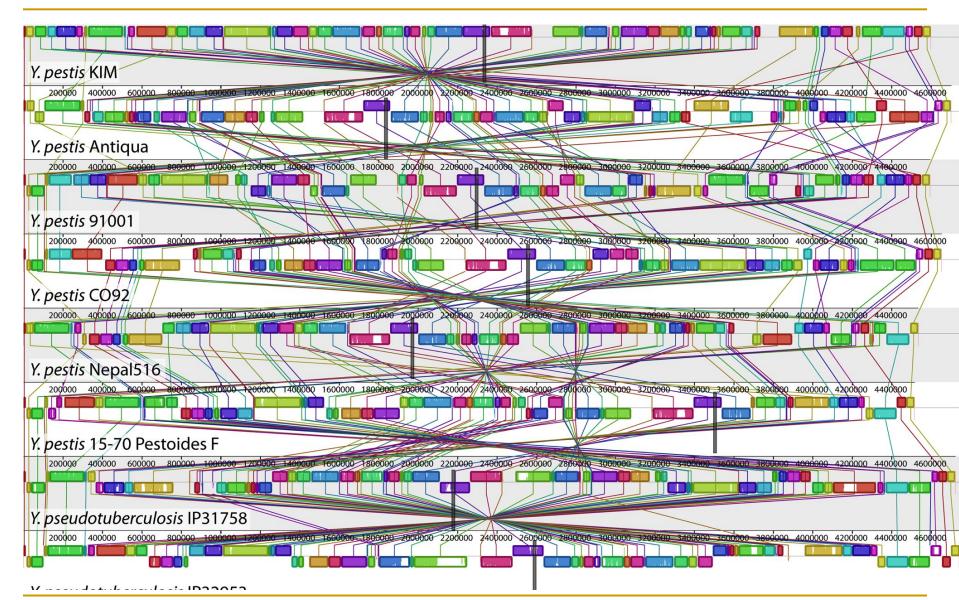








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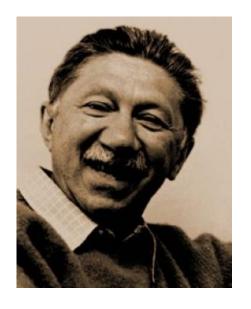


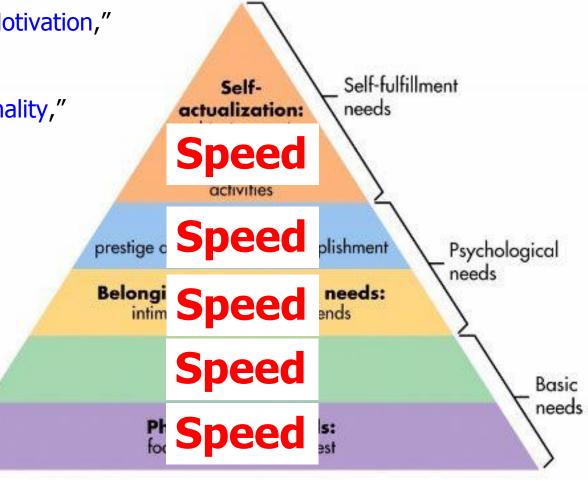


Maslow's Hierarchy of Needs, A Third Time

Maslow, "A Theory of Human Motivation," Psychological Review, 1943.

Maslow, "Motivation and Personality," Book, 1954-1970.



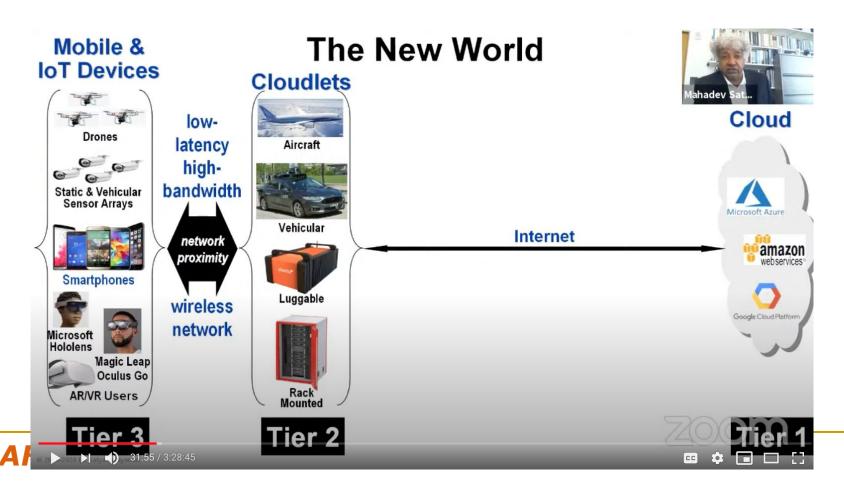


Challenge and Opportunity for Future

Fundamentally Low-Latency Computing Architectures

More Motivation for Low Latency

- Watch Satya's (CMU) keynote talk at SYSTOR 2020
 - https://youtu.be/u-KygYmbqDc?t=1723
 - Edge Computing: A New Disruptive Force



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Value Proposition of Edge Computing



What is the edge doing for you?

- 1. Edge analytics in IoT
 - "Scalable real-time sensor analytics"
- 2. Highly responsive cloud-like services "New applications and microservices"
- 3. Exposure firewall in the IoT

"Crossing the IoT Chasm"

4. Mask disruption of cloud services

"Disconnected operation for cloud services"

5. Honor data export restrictions

Bandwidth

(peak and average)

Latency

(mean and tail)

Privacy

(control of sensor data)

Availability

(UPS for cloud)

Provenance Full screen (f) (bring processing to the data)

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Human Cognition is Amazing

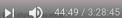


Fast, accurate and robust

- face detection under hostile conditions < 700 ms (low lighting, distorted optics)
 - face recognition 370 ms 620 ms
 - · is this sound from a human? 4 ms
 - VR head tracking < 16 ms

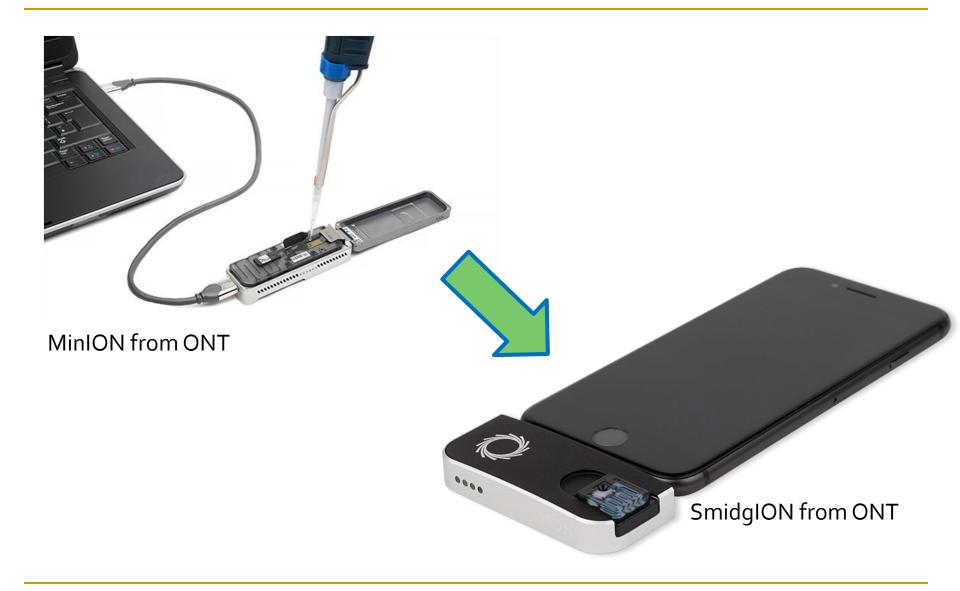
To be "superhuman" we need to beat these speeds

Leave time for additional software processing (e.g. database lookup) to add value to user





Future of Genome Sequencing & Analysis



Recall Our Dream (from 2007)

- An embedded device that can perform comprehensive genome analysis in real time (within a minute)
- Still a long ways to go
 - Energy efficiency
 - Performance (latency)
 - Security
 - Huge memory bottleneck

Data-Centric (Memory-Centric) Architectures

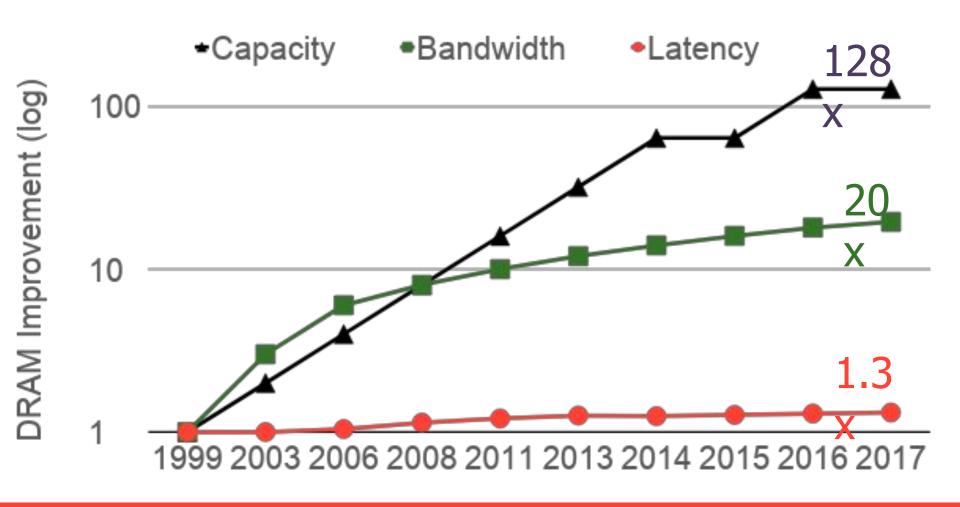
Data-Centric Architectures: Properties

- Process data where it resides (where it makes sense)
 - Processing in and near memory structures
- Low-latency & low-energy data access
 - Low latency memory
 - Low energy memory
- Low-cost data storage & processing
 - High capacity memory at low cost: hybrid memory, compression
- Intelligent data management
 - Intelligent controllers handling robustness, security, cost, scaling

Low-Latency & Low-Energy Data Access

Memory Latency: Fundamental Tradeoffs

Review: Memory Latency Lags Behind



Memory latency remains almost constant

A Closer Look ...

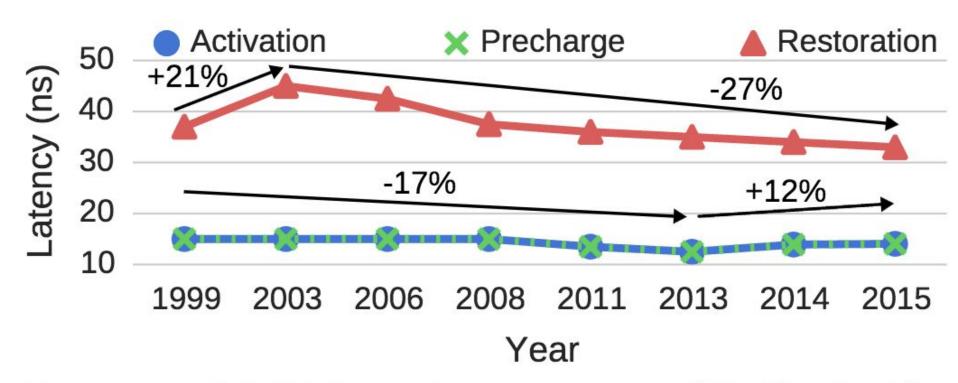


Figure 1: DRAM latency trends over time [20, 21, 23, 51].

Chang+, "Understanding Latency Variation in Modern DRAM Chips: Experimental Characterization, Analysis, and Optimization"," SIGMETRICS 2016.

DRAM Latency Is Critical for Performance



In-memory Databases

[Mao+, EuroSys'12; Clapp+ (Intel), IISWC'15]



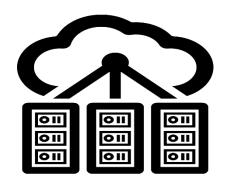
In-Memory Data Analytics

[Clapp+ (Intel), IISWC'15; Awan+, BDCloud'15]



Graph/Tree Processing

[Xu+, IISWC'12; Umuroglu+, FPL'15]



Datacenter Workloads

[Kanev+ (Google), ISCA'I5]

DRAM Latency Is Critical for Performance







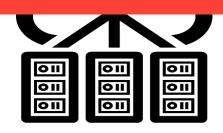
Graph/Tree Processing

Long memory latency → performance bottleneck





[Clapp+ (Intel), IISWC'15; Awan+, BDCloud'15]



Datacenter Workloads

[Kanev+ (Google), ISCA'15]

New DRAM Types Increase Latency!

Saugata Ghose, Tianshi Li, Nastaran Hajinazar, Damla Senol Cali, and Onur Mutlu, "Demystifying Workload-DRAM Interactions: An Experimental Study" Proceedings of the <u>ACM International Conference on Measurement and Modeling</u> of Computer Systems (SIGMETRICS), Phoenix, AZ, USA, June 2019.

Preliminary arXiv Version

Abstract

Slides (pptx) (pdf)

MemBen Benchmark Suite

Source Code for GPGPUSim-Ramulator

Demystifying Complex Workload-DRAM Interactions: **An Experimental Study**

Saugata Ghose[†]

Tianshi Li[†]

Nastaran Hajinazar^{‡†}

Damla Senol Cali[†] Onur Mutlu^{§†}

[†]Carnegie Mellon University

[‡]Simon Fraser University

§ETH Zürich

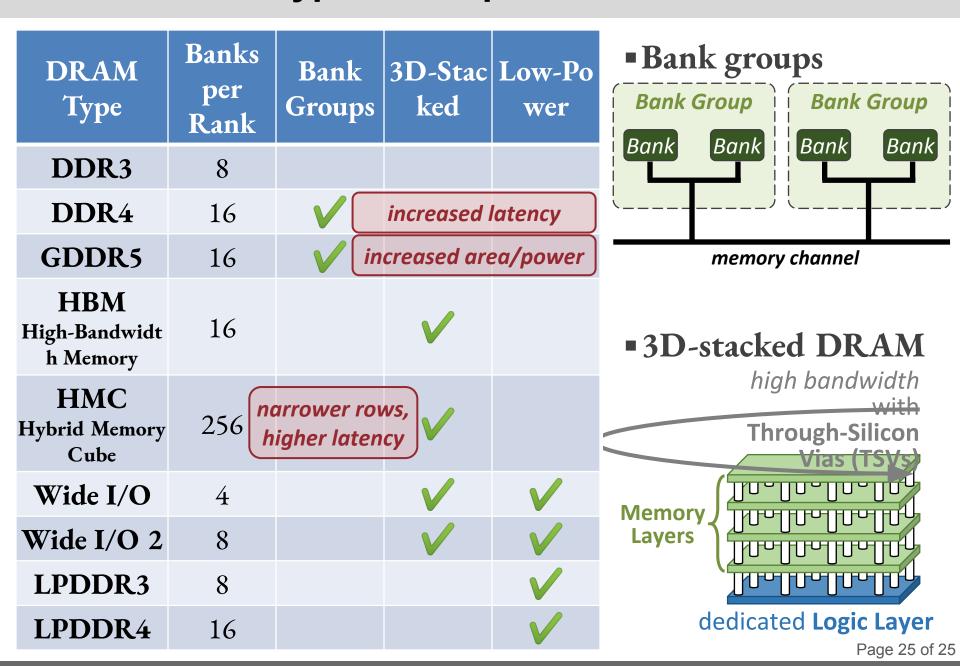
Why Study Workload–DRAM Interactions?



- Manufacturers are developing many new types of DRAM
 - DRAM limits performance, energy improvements: new types may overcome some limitations
 - Memory systems now serve a **very diverse set of applications:** can no longer take a one-size-fits-all approach
- So which DRAM type works best with which application?
 - Difficult to understand intuitively due to the complexity of the interaction
 - Can't be tested methodically on real systems: new type needs a new CPU
- We perform a wide-ranging experimental study to uncover the combined behavior of workloads and DRAM types
 - 115 prevalent/emerging applications and multiprogrammed workloads
 - 9 modern DRAM types: DDR3, DDR4, GDDR5, HBM, HMC, LPDDR3, LPDDR4, Wide I/O, Wide I/O 2

Modern DRAM Types: Comparison to DDR3



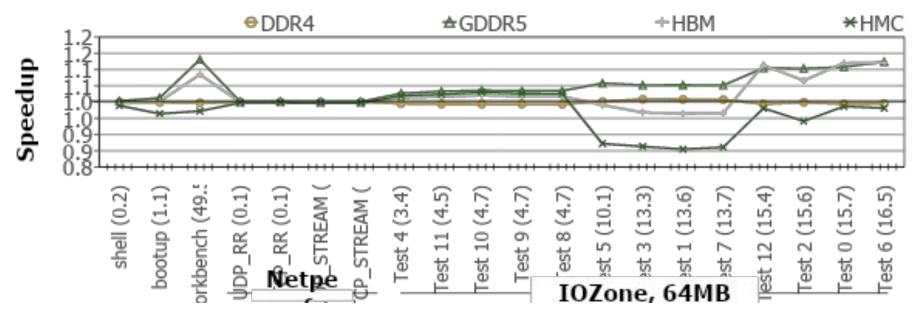


4. Need for Lower Access Latency:

SAFARI

Performance

- New DRAM types often increase access latency in order to provide more banks, higher throughput
- Many applications can't make up for the increased latency
 - Especially true of common OS routines (e.g., file I/O, process forking)



• A variety of desktop/scientific, server/cloud, GPGPU applications

Several applications don't benefit from more parallelism

- 1. DRAM latency remains a critical bottleneck for many applications
- 2. Bank parallelism is not fully utilized by a wide variety of our applications
- 3. Spatial locality continues to provide significant performance benefits if it is exploited by the memory subsystem
- 4. For some classes of applications, low-power memory can provide energy savings without sacrificing significant performance

- Manufacturers are developing many new types of DRAM
 - DRAM limits performance, energy improvements: new types may overcome some limitations
 - Memory systems now serve a **very diverse set of applications:** can no longer take a one-size-fits-all approach
 - Difficult to intuitively determine which DRAM-workload pair works best
- We perform a wide-ranging experimental study to uncover the combined behavior of workloads, DRAM types
 - 115 prevalent/emerging applications and multiprogrammed workloads
 - •9 modern DRAM types
- 12 key observations on DRAM—workload behavior

Open-source tools: https://github.com/CMU-SAFARI/ramulator
Full paper: https://arxiv.org/pdf/1902.07609

New DRAM Types Increase Latency!

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The Memory Latency Problem

- High memory latency is a significant limiter of system performance and energy-efficiency
- It is becoming increasingly so with higher memory contention in multi-core and heterogeneous architectures
 - Exacerbating the bandwidth need
 - Exacerbating the QoS problem
- It increases processor design complexity due to the mechanisms incorporated to tolerate memory latency

Retrospective: Conventional Latency Tolerance Techniques

- Caching [initially by Wilkes, 1965]
 - Widely used, simple, effective, but inefficient, passive
 - Not all applications/phases exhibit temporal or spatial locality
- Prefetching [initially in IBM 360/91, 1967]
 - Works well for regular memory access patterns
 - Prefetching irregular access patterns is difficult, inaccurate, and hardware-intensive
- Multithreading [initially in CDC 6600, 1964]
 - Works well if there are multiple threads
 - Improving single thread performance using multithreading hardware is an ongoing research effort
- Out-of-order execution [initially by Tomasulo, 1967]
 - Tolerates cache misses that cannot be prefetched
 - Requires extensive hardware resources for tolerating long latencies

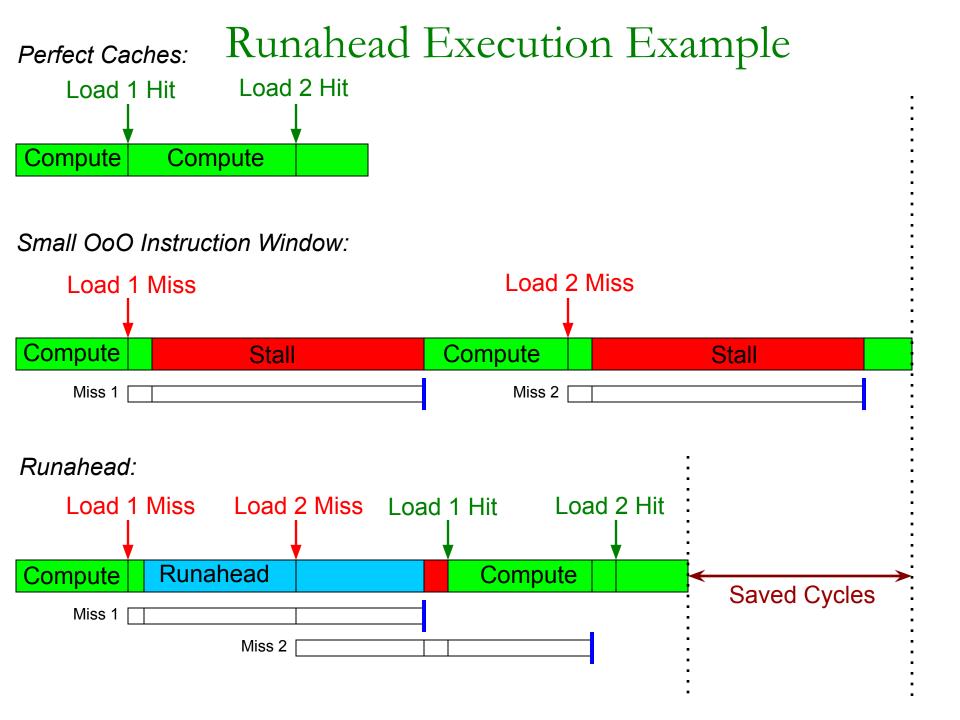


Retrospective: Conventional Latency Tolerance Techniques

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 Fundamentally Reduce Memory
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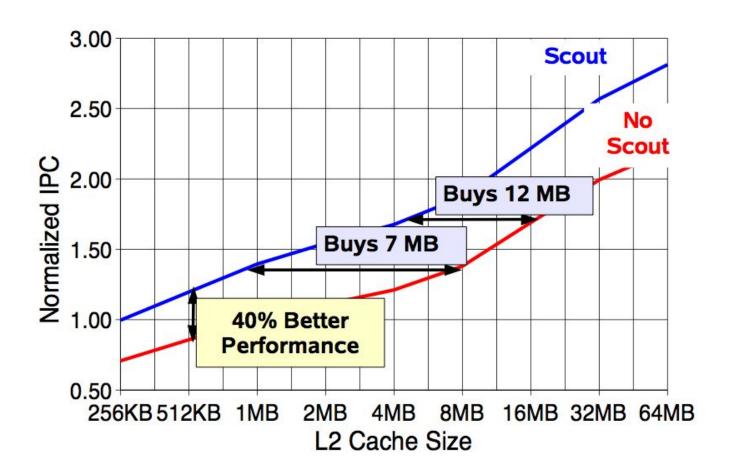


Runahead Execution



Effect of Runahead in Sun ROCK

Shailender Chaudhry talk, Aug 2008.



More on Runahead Execution

Onur Mutlu, Jared Stark, Chris Wilkerson, and Yale N. Patt,
 "Runahead Execution: An Alternative to Very Large Instruction
 Windows for Out-of-order Processors"
 Proceedings of the <u>9th International Symposium on High-Performance</u>
 <u>Computer Architecture</u> (HPCA), Anaheim, CA, February 2003. <u>Slides (pdf)</u>
 One of the 15 computer architecture papers of 2003 selected as Top Picks by IEEE Micro.

Runahead Execution: An Alternative to Very Large Instruction Windows for Out-of-order Processors

Onur Mutlu § Jared Stark † Chris Wilkerson ‡ Yale N. Patt §

§ECE Department
The University of Texas at Austin
{onur,patt}@ece.utexas.edu

†Microprocessor Research Intel Labs jared.w.stark@intel.com

‡Desktop Platforms Group Intel Corporation chris.wilkerson@intel.com

More on Runahead Execution (Short)

Onur Mutlu, Jared Stark, Chris Wilkerson, and Yale N. Patt,
 "Runahead Execution: An Effective Alternative to Large Instruction Windows"

<u>IEEE Micro, Special Issue: Micro's Top Picks from Microarchitecture</u> <u>Conferences</u> (**MICRO TOP PICKS**), Vol. 23, No. 6, pages 20-25, November/December 2003.

RUNAHEAD EXECUTION: AN EFFECTIVE ALTERNATIVE TO LARGE INSTRUCTION WINDOWS

Runahead Readings

Required

Mutlu et al., "Runahead Execution", HPCA 2003, Top Picks 2003.

Recommended

- Mutlu et al., "Efficient Runahead Execution: Power-Efficient Memory Latency Tolerance," ISCA 2005, IEEE Micro Top Picks 2006.
- Mutlu et al., "Address-Value Delta (AVD) Prediction," MICRO 2005.
- Armstrong et al., "Wrong Path Events," MICRO 2004.

Retrospective: Conventional Latency Tolerance Techniques

Caching [initially by Wilkes, 1965]

Morkey

- Widely used, simple, effective, but inefficient, passive
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 Fundamentally Reduce
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Two Major Sources of Latency Inefficiency

- Modern DRAM is not designed for low latency
 - Main focus is cost-per-bit (capacity)
- Modern DRAM latency is determined by worst case conditions and worst case devices
 - Much of memory latency is unnecessary

Our Goal: Reduce Memory Latency at the Source of the Problem

Truly Reducing Memory Latency

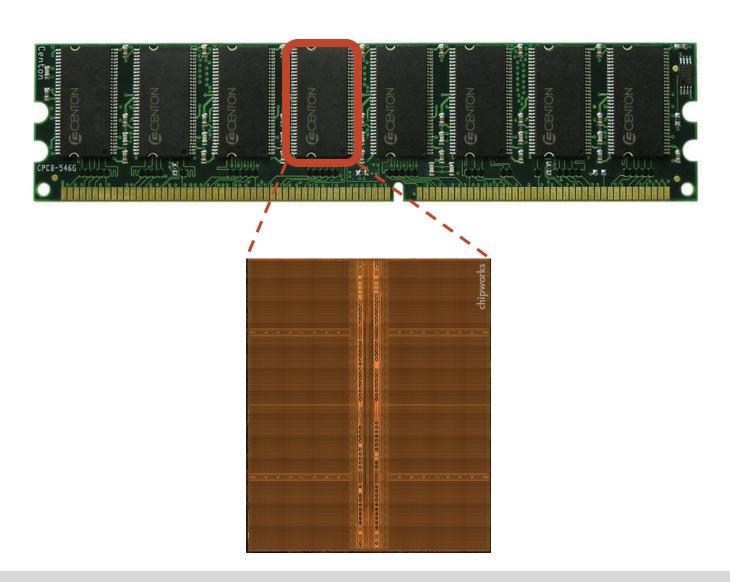
What Causes the Long Memory Latency?

Why the Long Memory Latency?

- Reason 1: Design of DRAM Micro-architecture
 - Goal: Maximize capacity/area, not minimize latency
- Reason 2: "One size fits all" approach to latency specification
 - Same latency parameters for all temperatures
 - Same latency parameters for all DRAM chips
 - Same latency parameters for all parts of a DRAM chip
 - Same latency parameters for all supply voltage levels
 - Same latency parameters for all application data

Brief Review: Inside A DRAM Chip

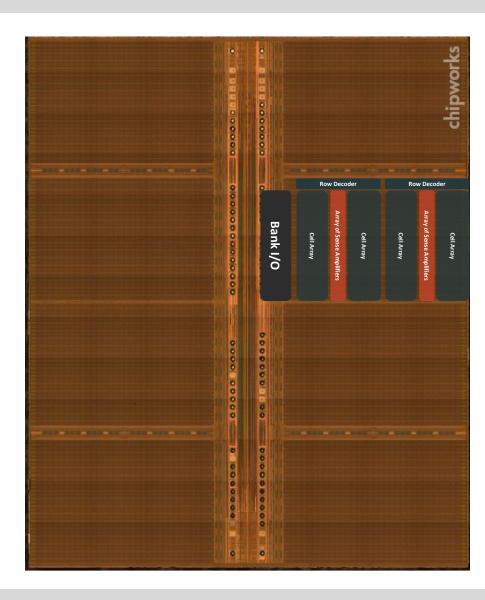
DRAM Module and Chip



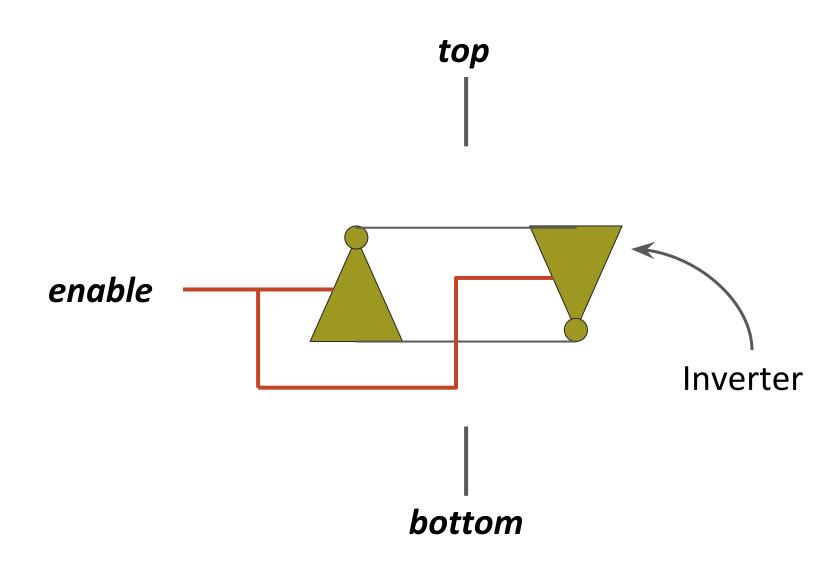
Goals

- Cost
- Latency
- Bandwidth
- Parallelism
- Power
- Energy
- Reliability
- . . .

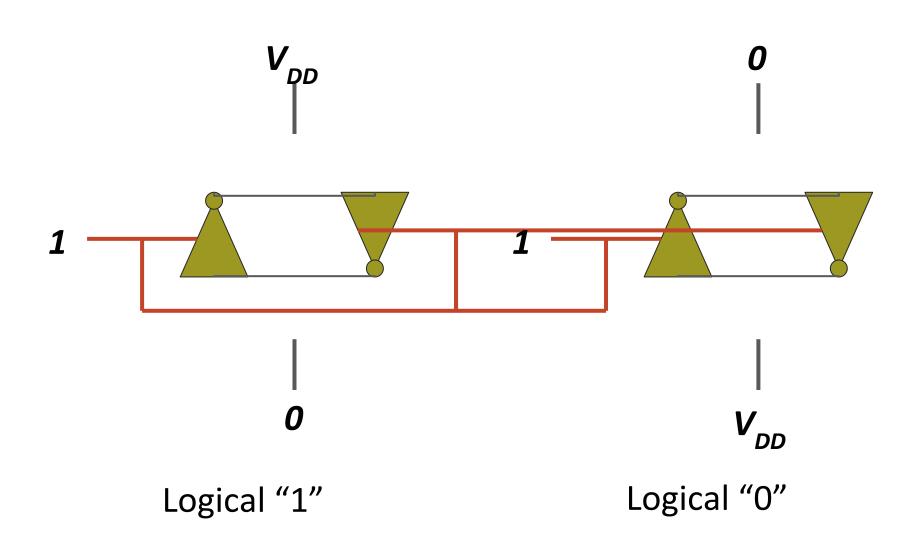
DRAM Chip



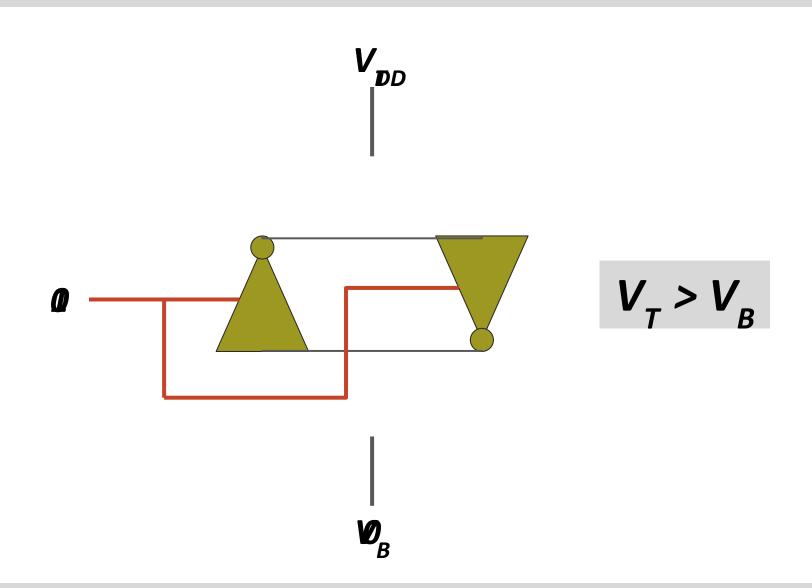
Sense Amplifier



Sense Amplifier – Two Stable States

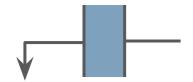


Sense Amplifier Operation



DRAM Cell – Capacitor





Empty State

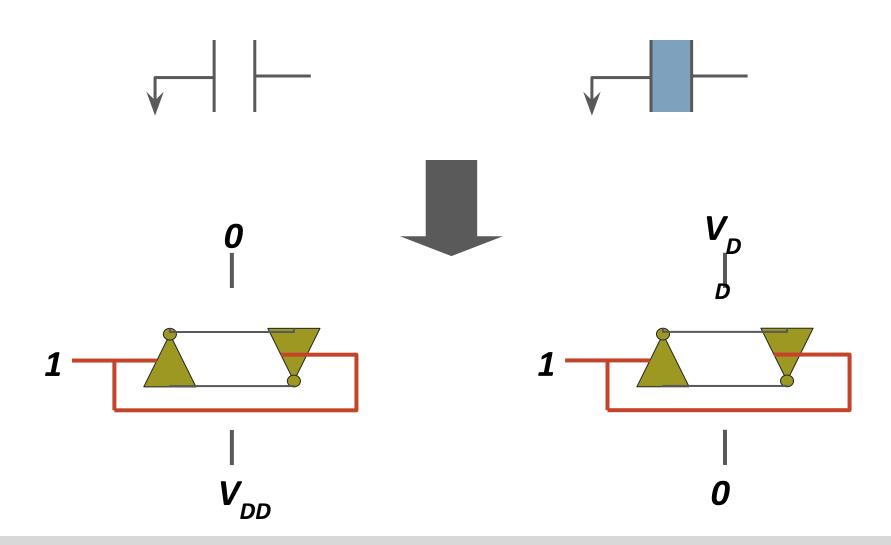
Logical "0"

Fully Charged State

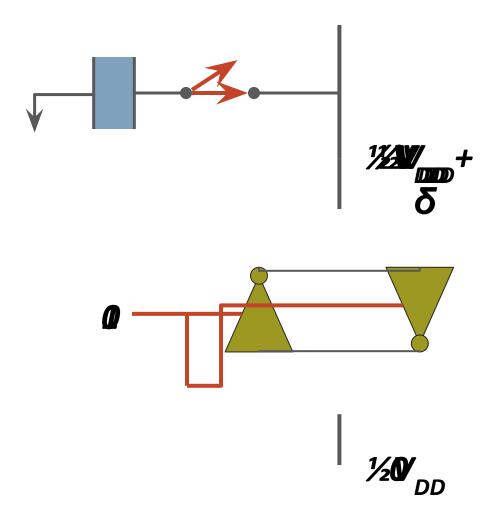
Logical "1"

- Small Cannot drive circuits
- Reading destroys the state

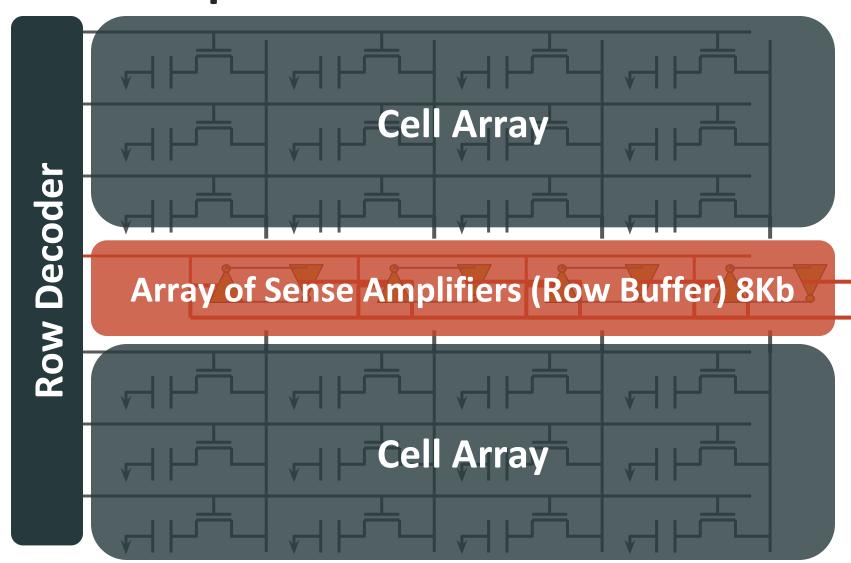
Capacitor to Sense Amplifier



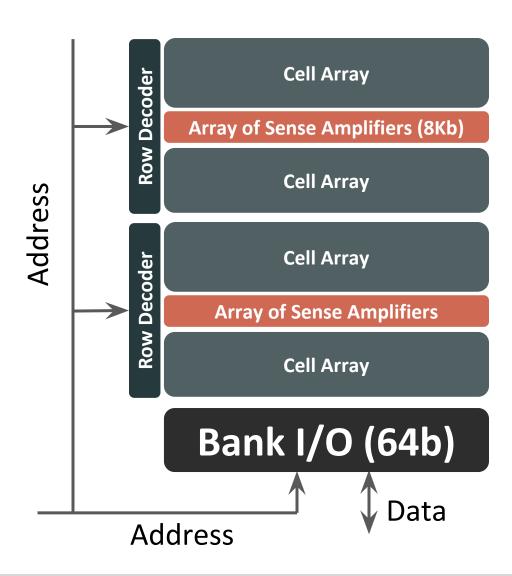
DRAM Cell Operation



DRAM Subarray – Building Block for DRAM Chip



DRAM Bank



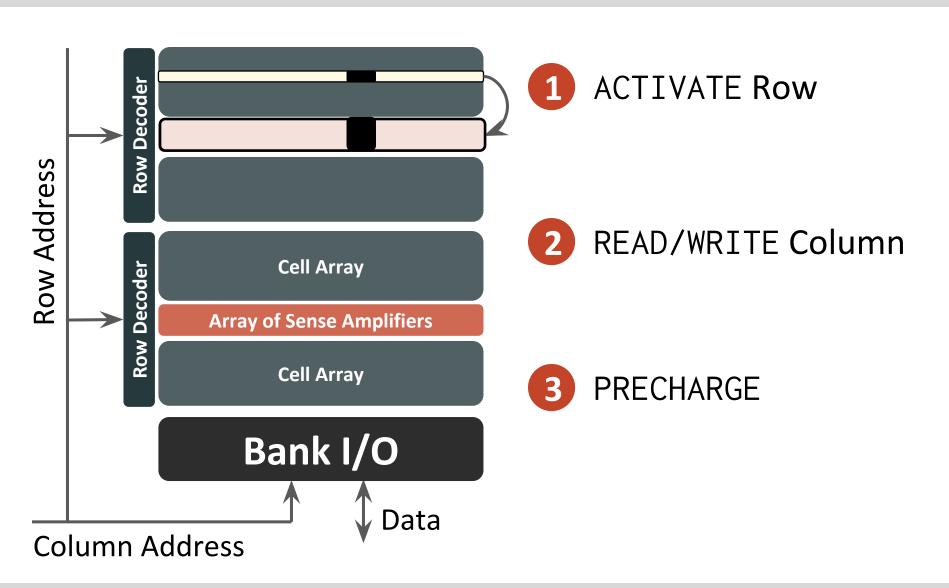
DRAM Chip

Shared internal bus



Memory channel - 8bits ←

DRAM Operation



More on DRAM Operation: Section 2

 Vivek Seshadri and Onur Mutlu, "In-DRAM Bulk Bitwise Execution Engine"

Invited Book Chapter in Advances in Computers, to appear in 2020.

[Preliminary arXiv version]

In-DRAM Bulk Bitwise Execution Engine

Vivek Seshadri Microsoft Research India visesha@microsoft.com Onur Mutlu
ETH Zürich
onur.mutlu@inf.ethz.ch

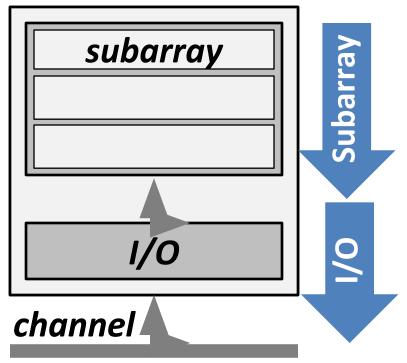
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Tiered Latency DRAM

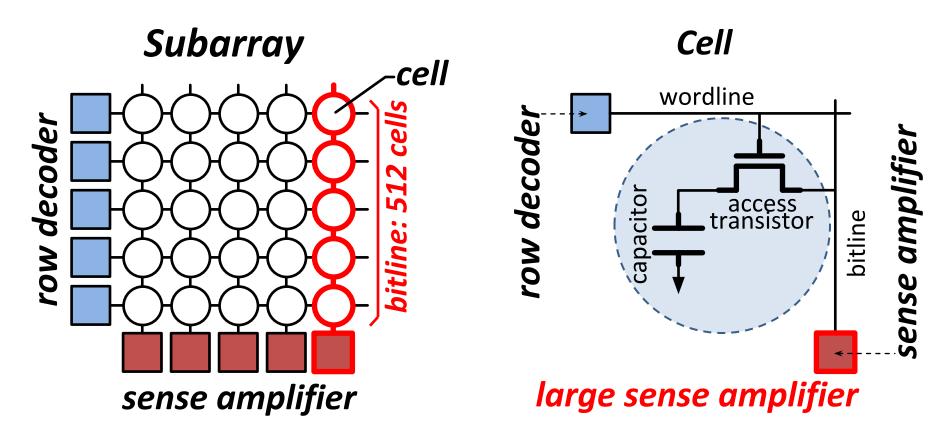
What Causes the Long Latency?

DRAM Chip





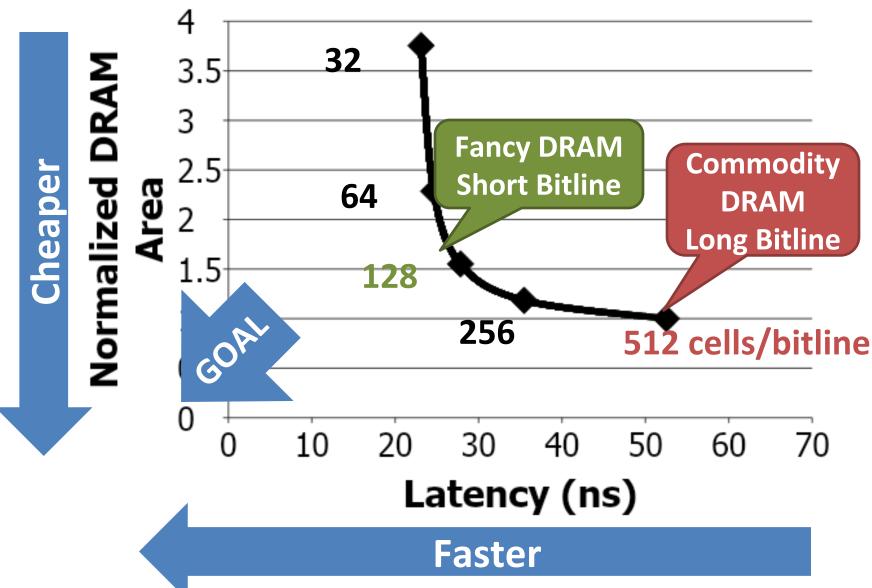
Why is the Subarray So Slow?



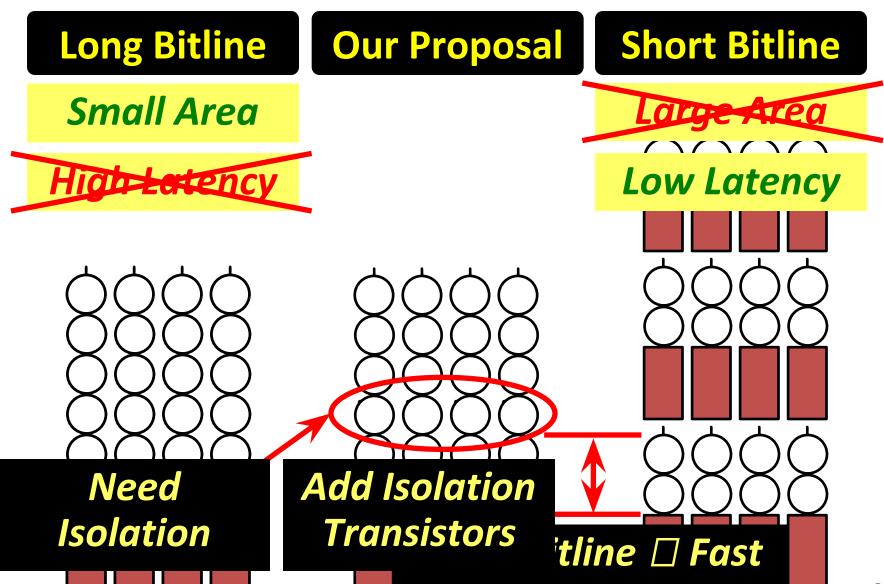
- Long bitline
 - Amortizes sense amplifier cost □ Small area
 - Large bitline capacitance
 High latency & power

Trade-Off: Area (Die Size) vs. Latency **Short Bitline Long Bitline Faster Smaller** Trade-Off: Area vs. Latency

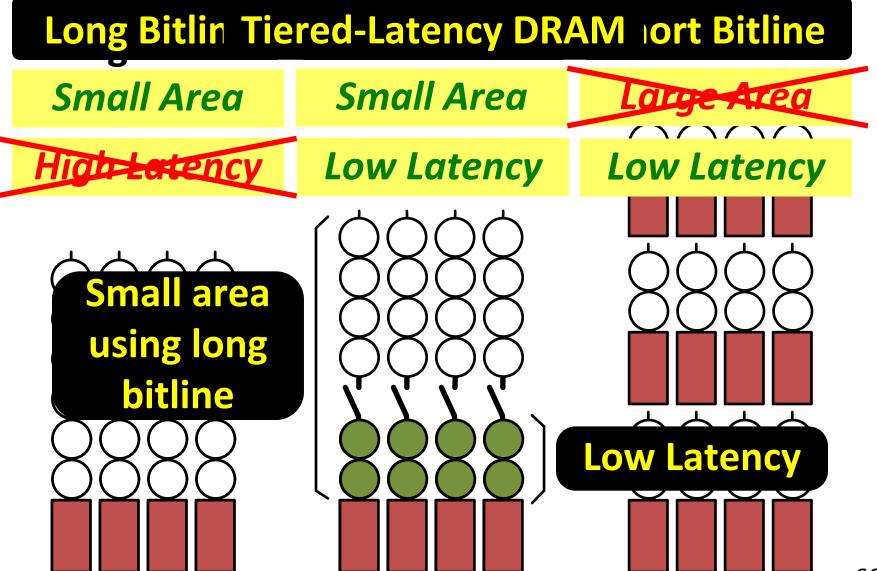
Trade-Off: Area (Die Size) vs. Latency



Approximating the Best of Both Worlds

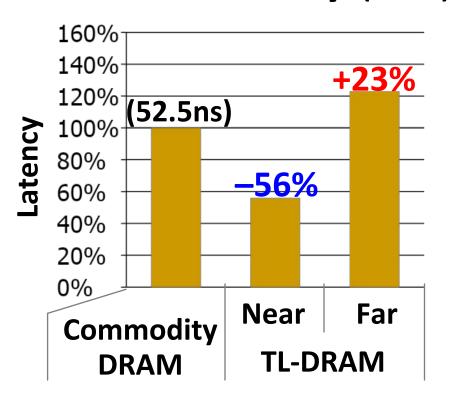


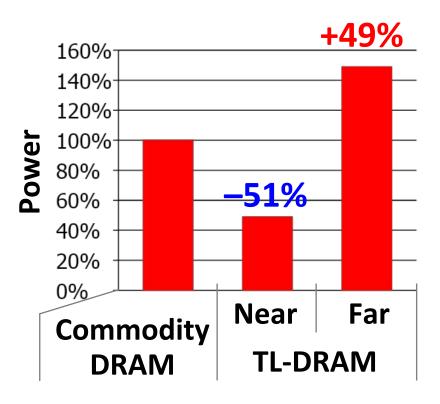
Approximating the Best of Both Worlds



Commodity DRAM vs. TL-DRAM [HPCA 2013]

DRAM Latency (tRC)
 DRAM Power

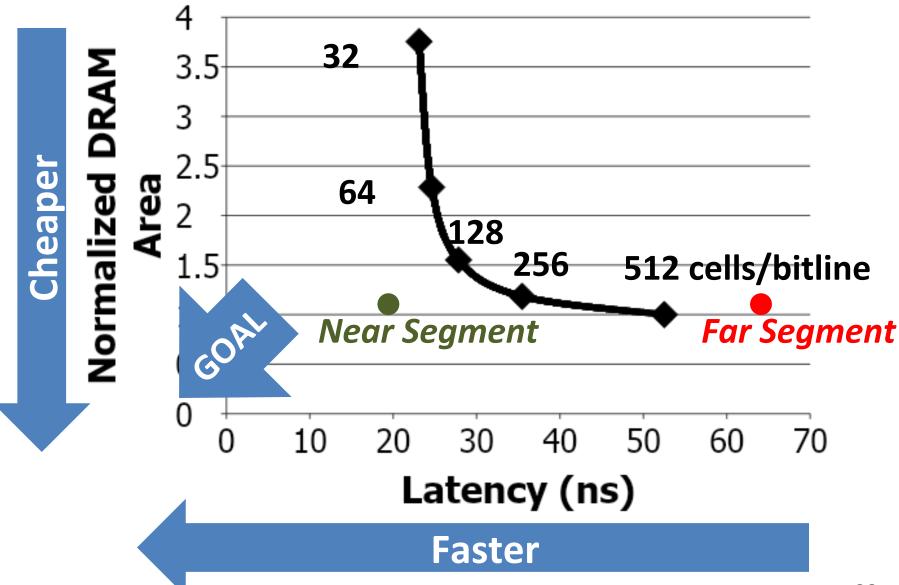




DRAM Area Overhead

~3%: mainly due to the isolation transistors

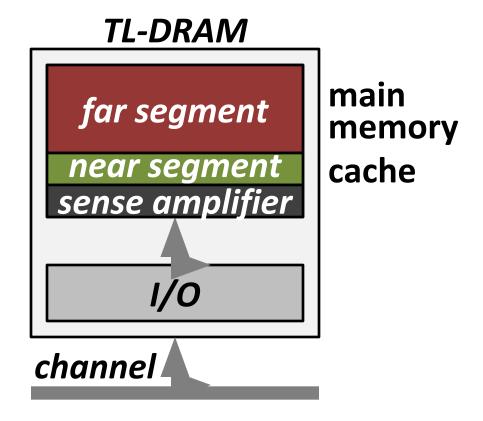
Trade-Off: Area (Die-Area) vs. Latency



Leveraging Tiered-Latency DRAM

- TL-DRAM is a substrate that can be leveraged by the hardware and/or software
- Many potential uses
 - Use near segment as hardware-managed inclusive cache to far segment
 - Use near segment as hardware-managed exclusive cache to far segment
 - Profile-based page mapping by operating system
 - 4. Simply replace DRAM with TL-DRAM

Near Segment as Hardware-Managed Cache

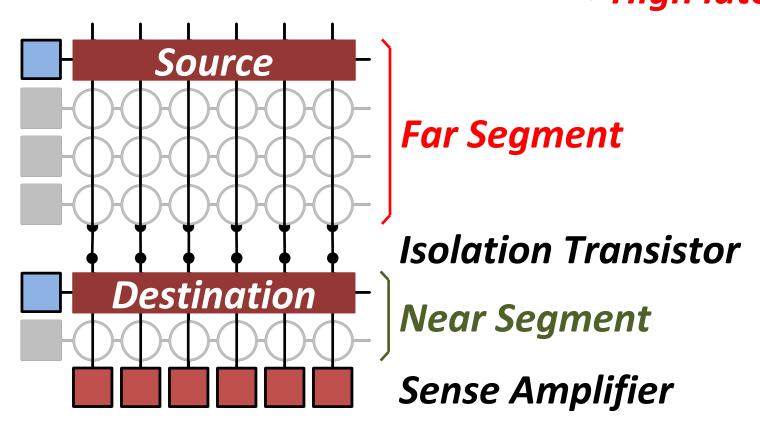


- Challenge 1: How to efficiently migrate a row between segments?
- Challenge 2: How to efficiently manage the cache?

Inter-Segment Migration

- Goal: Migrate source row into destination row
- Naïve way: Memory controller reads the source row byte by byte and writes to destination row byte by byte

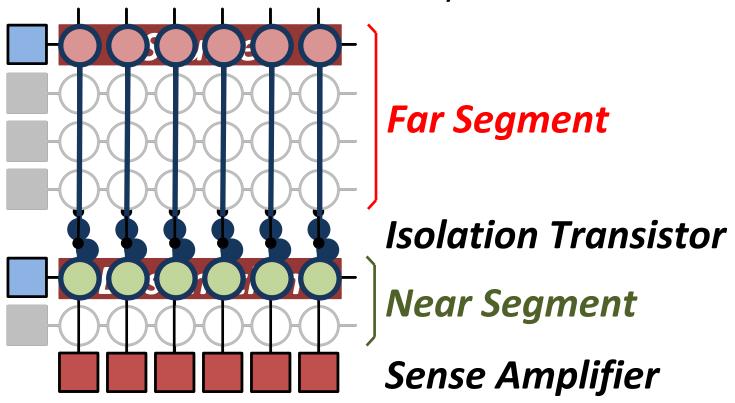
 → High latency



Inter-Segment Migration

Our way:

- Source and destination cells share bitlines
- Transfer data from source to destination across shared bitlines concurrently



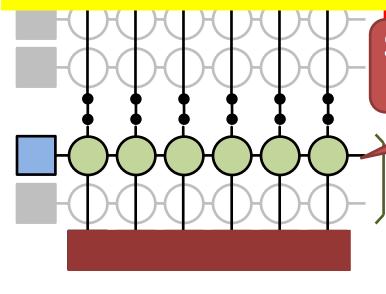
Inter-Segment Migration

Our way:

- Source and destination cells share bitlines
- Transfer data from so shared bitlines concu

 Step 1: Activate source row

Migration is overlapped with source row access Additional ~4ns over row access latency

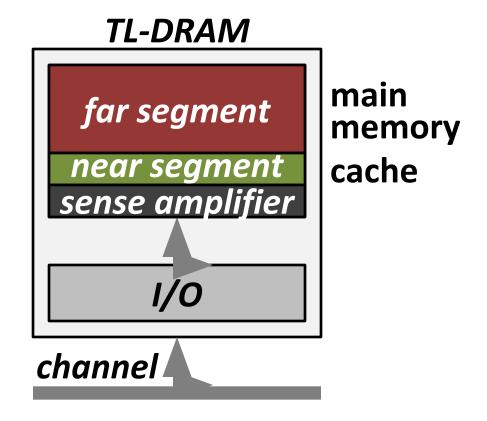


Step 2: Activate destination row to connect cell and bitline

Near Segment

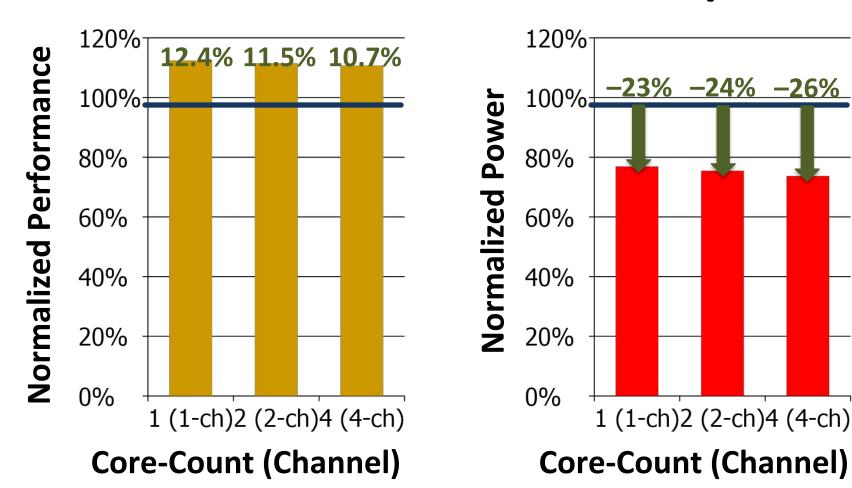
Sense Amplifier

Near Segment as Hardware-Managed Cache



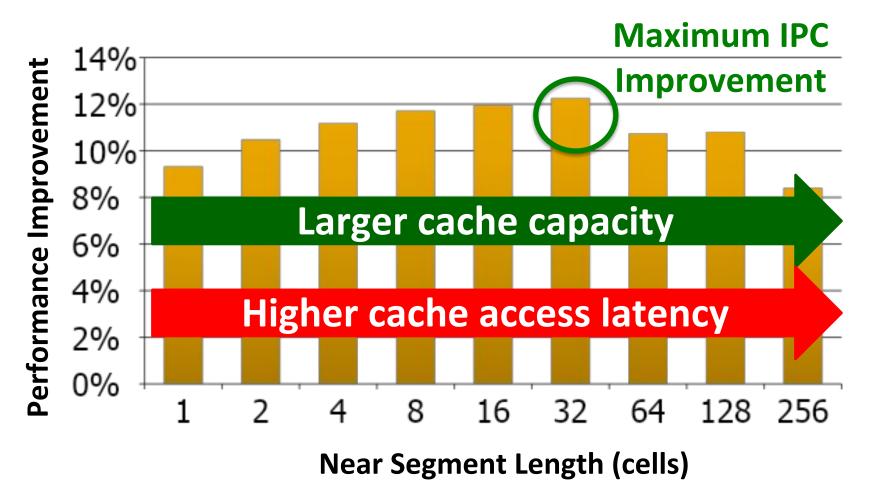
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Performance & Power Consumption



Using near segment as a cache improves performance and reduces power consumption

Single-Core: Varying Near Segment Length



By adjusting the near segment length, we can trade off cache capacity for cache latency

More on TL-DRAM

 Donghyuk Lee, Yoongu Kim, Vivek Seshadri, Jamie Liu, Lavanya Subramanian, and Onur Mutlu,

"Tiered-Latency DRAM: A Low Latency and Low Cost DRAM Architecture"

Proceedings of the <u>19th International Symposium on</u> <u>High-Performance Computer Architecture</u> (**HPCA**), Shenzhen, China, February 2013. <u>Slides (pptx)</u>

Tiered-Latency DRAM: A Low Latency and Low Cost DRAM Architecture

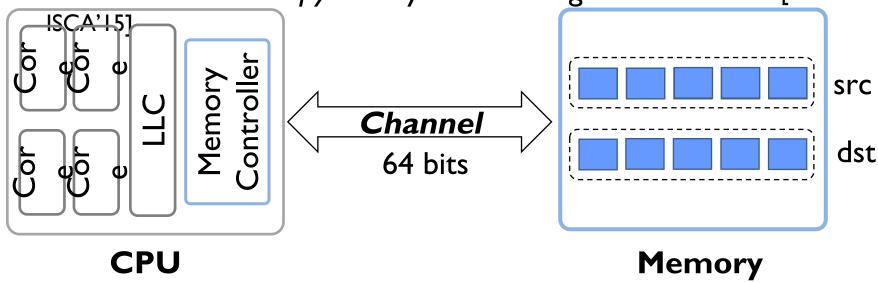
Donghyuk Lee Yoongu Kim Vivek Seshadri Jamie Liu Lavanya Subramanian Onur Mutlu Carnegie Mellon University

LISA: Low-Cost Inter-Linked Subarrays [HPCA 2016]

Problem: Inefficient Bulk Data Movement

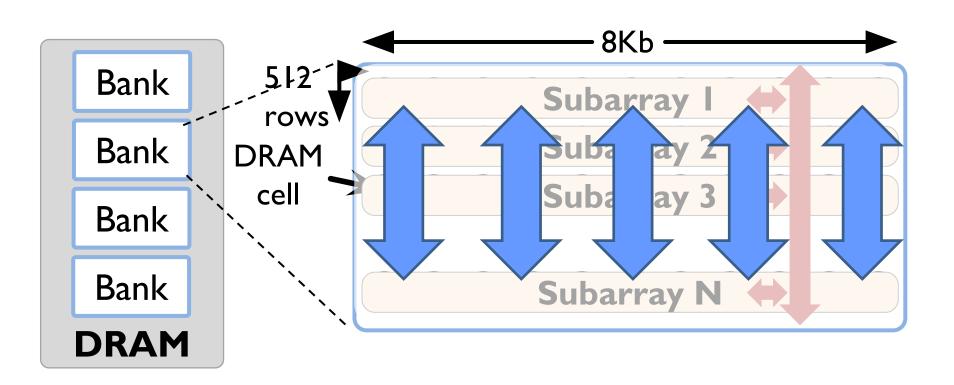
Bulk data movement is a key operation in many applications

- memmove & memcpy: 5% cycles in Google's datacenter [Kanev+



Long latency and high energy

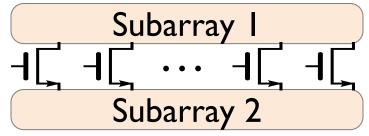
Moving Data Inside DRAM?



Goal: Provide a new substrate to enable wide connectivity between subarrays

Key Idea and Applications

- Low-cost Inter-linked subarrays (LISA)
 - Fast bulk data movement between subarrays
 - Wide datapath via isolation transistors: 0.8% DRAM chip area



LISA is a versatile substrate → new applications

Fast bulk data copy: Copy latency $1.363 \text{ms} \rightarrow 0.148 \text{ms} (9.2 \text{x})$

→ 66% speedup, -55% DRAM energy

In-DRAM caching: Hot data access latency $48.7 \text{ns} \rightarrow 21.5 \text{ns}$ (2.2x)

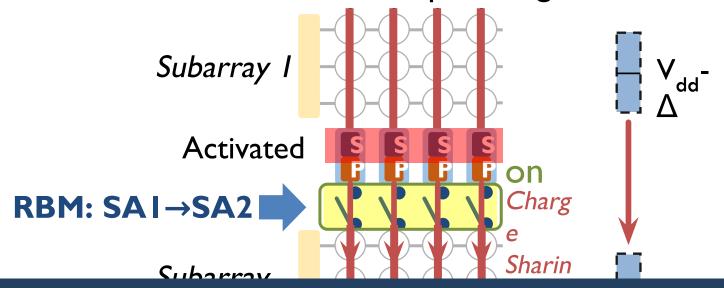
→ 5% speedup

Fast precharge: Precharge latency 13.1ns→5.0ns (2.6x)

→ 8% speedup

New DRAM Command to Use LISA

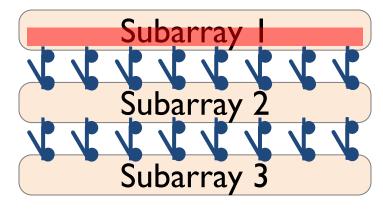
Row Buffer Movement (RBM): Move a row of data in an activated row buffer to a precharged one



RBM transfers an entire row b/w subarrays

RBM Analysis

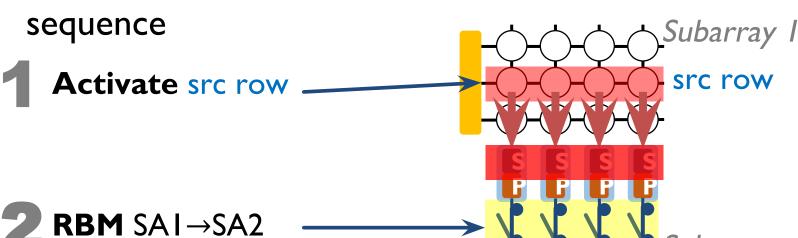
- The range of RBM depends on the DRAM design
 - Multiple RBMs to move data across > 3 subarrays



- Validated with SPICE using worst-case cells
 - NCSU FreePDK 45nm library
 - 4KB data in 8ns (w/ 60% guardband)
 - → 500 GB/s, 26x bandwidth of a DDR4-2400 channel
 - 0.8% DRAM chip area overhead [O+ISCA'14]

1. Rapid Inter-Subarray Copying (RISC)

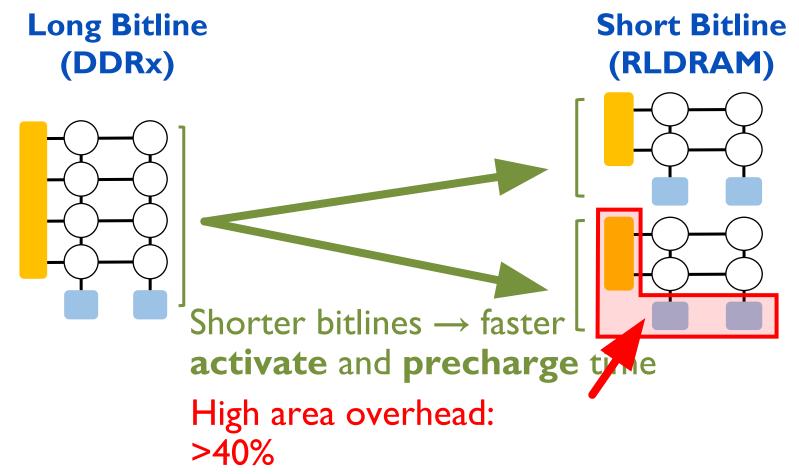
- Goal: Efficiently copy a row across subarrays
- Key idea: Use RBM to form a new command



Reduces row-copy latency by 9.2x, DRAM energy by 48.1x

2. Variable Latency DRAM (VILLA)

- Goal: Reduce DRAM latency with low area overhead
- Motivation: Trade-off between area and latency



2. Variable Latency DRAM (VILLA)

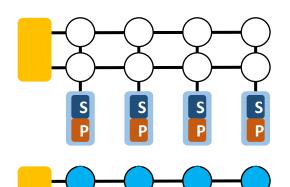
- Key idea: Reduce access latency of hot data via a heterogeneous DRAM design [Lee+ HPCA'13, Son+ ISCA'13]
- **VILLA**: Add fast subarrays as a **cache** in each bank

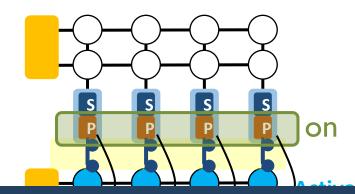


Reduces hot data access latency by 2.2x at only 1.6% area overhead

3. Linked Precharge (LIP)

- **Problem**: The precharge time is limited by the strength of one precharge unit
- <u>Linked Precharge (LIP)</u>: LISA precharges a subarray using multiple precharge units





Reduces precharge latency by 2.6x (43% guardband)

More on LISA

 Kevin K. Chang, Prashant J. Nair, Saugata Ghose, Donghyuk Lee, Moinuddin K. Qureshi, and Onur Mutlu,

"Low-Cost Inter-Linked Subarrays (LISA): Enabling Fast Inter-Subarray Data Movement in DRAM"

Proceedings of the <u>22nd International Symposium on</u>
<u>High-Performance Computer Architecture</u> (**HPCA**), Barcelona, Spain,
March 2016.

[Slides (pptx) (pdf)]
[Source Code]

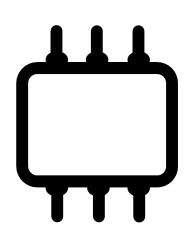
Low-Cost Inter-Linked Subarrays (LISA): Enabling Fast Inter-Subarray Data Movement in DRAM

Kevin K. Chang[†], Prashant J. Nair*, Donghyuk Lee[†], Saugata Ghose[†], Moinuddin K. Qureshi*, and Onur Mutlu[†]

†Carnegie Mellon University *Georgia Institute of Technology

CROW: The Copy Row Substrate [ISCA 2019]

Challenges of DRAM Scaling



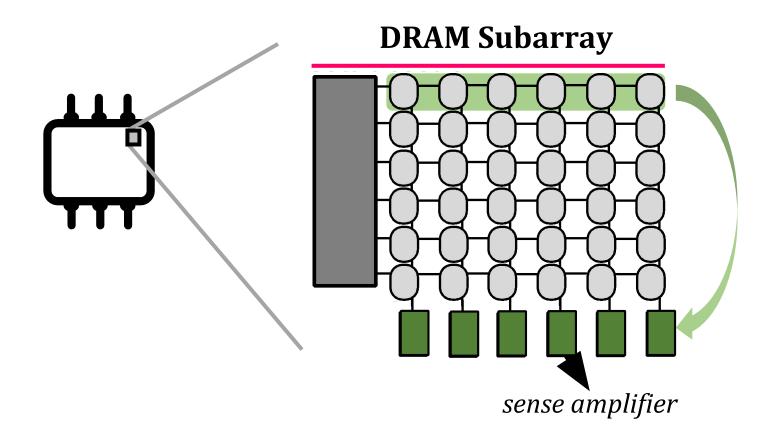
- 1 access latency
- 2 refresh overhead

3 exposure to vulnerabilities





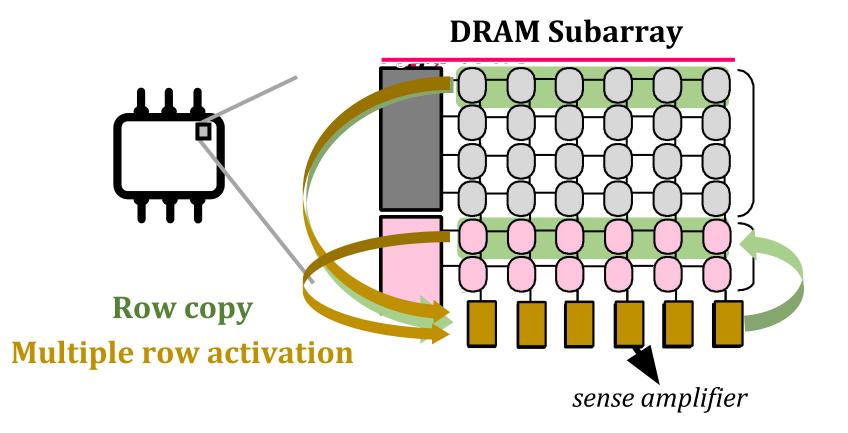
Conventional DRAM







Copy Row DRAM (CROW)



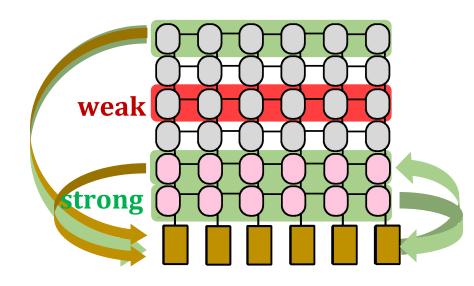




Use Cases of CROW

CROW-cache

✓ reduces access latency



CROW-ref

✓ reduces DRAM refresh overhead

□A mechanism for protecting against *RowHammer*





Key Results

CROW-cache + CROW-ref

- •20% speedup
- •22% less DRAM energy

Hardware Overhead

- •0.5% DRAM chip area
- •1.6% DRAM capacity
- •11.3 KiB memory controller storage





More on CROW

Hasan Hassan, Minesh Patel, Jeremie S. Kim, A. Giray Yaglikci, Nandita Vijaykumar,
 Nika Mansourighiasi, Saugata Ghose, and Onur Mutlu,

"CROW: A Low-Cost Substrate for Improving DRAM Performance, Energy Efficiency, and Reliability"

Proceedings of the <u>46th International Symposium on Computer Architecture</u> (**ISCA**), Phoenix, AZ, USA, June 2019.

[Slides (pptx) (pdf)]

[Lightning Talk Slides (pptx) (pdf)]

[Poster (pptx) (pdf)]

[Lightning Talk Video (3 minutes)]

[Full Talk Video (16 minutes)]

[Source Code for CROW (Ramulator and Circuit Modeling)]

CROW: A Low-Cost Substrate for Improving DRAM Performance, Energy Efficiency, and Reliability

Hasan Hassan[†] Minesh Patel[†] Jeremie S. Kim^{†§} A. Giray Yaglikci[†] Nandita Vijaykumar^{†§} Nika Mansouri Ghiasi[†] Saugata Ghose[§] Onur Mutlu^{†§}

†ETH Zürich [§] Carnegie Mellon University

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CLR-DRAM: Capacity-Latency Reconfigurability

Haocong Luo, Taha Shahroodi, Hasan Hassan, Minesh Patel, A. Giray Yaglikci, Lois Orosa, Jisung Park, and Onur Mutlu, "CLR-DRAM: A Low-Cost DRAM Architecture Enabling **Dynamic Capacity-Latency Trade-Off**"

Proceedings of the <u>47th International Symposium on Computer</u> Architecture (ISCA), Valencia, Spain, June 2020.

[Slides (pptx) (pdf)]

[Lightning Talk Slides (pptx) (pdf)]

[Talk Video (20 minutes)]

[Lightning Talk Video (3 minutes)]

CLR-DRAM: A Low-Cost DRAM Architecture **Enabling Dynamic Capacity-Latency Trade-Off**

Taha Shahroodi[§] Hasan Hassan[§] Haocong Luo§† Minesh Patel§ A. Giray Yağlıkçı[§] Lois Orosa[§] Jisung Park[§] Onur Mutlu[§]

§ETH Zürich †ShanghaiTech University



CLR-DRAM: Capacity-Latency Reconfigurable DRAM [ISCA 2020]

CLR-DRAM:

A Low-Cost DRAM Architecture Enabling Dynamic Capacity-Latency Trade-off

<u>Haocong Luo</u> Taha Shahroodi Hasan Hassan Minesh Patel A. Giray Yaglıkçı Lois Orosa Jisung Park Onur Mutlu

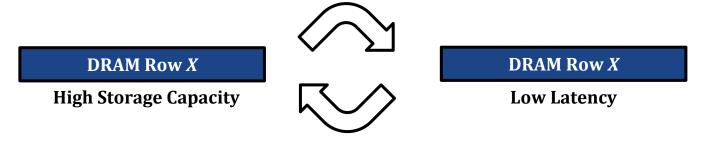






Motivation & Goal

- Workloads and systems have varying main memory capacity and latency demands.
- Existing commodity DRAM makes static capacity-latency trade-off at design time.
- Systems miss opportunities to improve performance by adapting to changes in main memory capacity and latency demands.
- **Goal**: Design a low-cost DRAM architecture that can be dynamically configured to have high capacity or low latency at a fine granularity (i.e., at the granularity of a row).



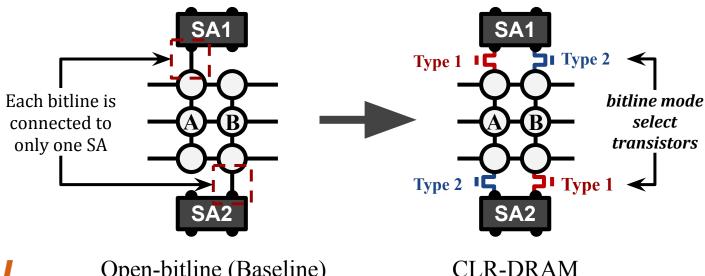


CLR-DRAM (<u>Capacity-Latency-Reconfigurable DRAM</u>)

- **CLR-DRAM (Capacity-Latency-Reconfigurable DRAM):**
 - A low cost DRAM architecture that enables a single DRAM row to *dynamically* switch between max-capacity mode or high-performance mode.

Key Idea:

Dynamically configure the connections between DRAM cells and sense amplifiers in the density-optimized open-bitline architecture.

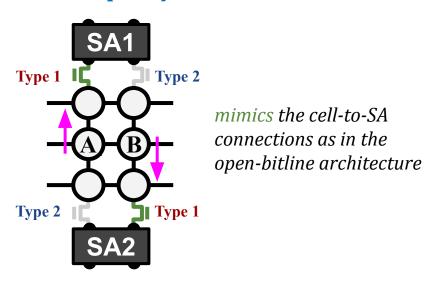




Open-bitline (Baseline)

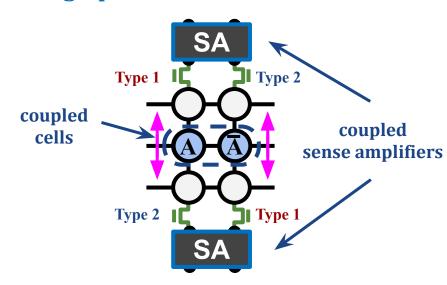
CLR-DRAM (Capacity-Latency-Reconfigurable DRAM)

Max-capacity mode



The same storage capacity as the conventional open-bitline architecture

• High-performance mode



Reduced latency and refresh overhead via coupled cell/SA operation



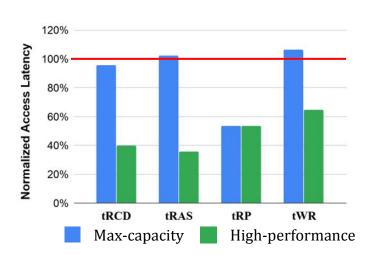
Key Results

• DRAM Latency Reduction:

- Activation latency (tRCD) by 60.1%
- Restoration latency (tRAS) by 64.2%
- Precharge latency (tRP) by 46.4%
- Write-recovery latency (tWR) by 35.2%

<u>System-level Benefits</u>:

- Performance improvement: 18.6%
- DRAM energy reduction: 29.7%
- DRAM refresh energy reduction: 66.1%



We hope that CLR-DRAM can be exploited to develop more flexible systems that can adapt to the diverse and changing DRAM capacity and latency demands of workloads.



More on CLR-DRAM

 Haocong Luo, Taha Shahroodi, Hasan Hassan, Minesh Patel, A. Giray Yaglikci, Lois Orosa, Jisung Park, and Onur Mutlu, "CLR-DRAM: A Low-Cost DRAM Architecture Enabling Dynamic Capacity-Latency Trade-Off"

Proceedings of the <u>47th International Symposium on Computer</u> <u>Architecture</u> (**ISCA**), Valencia, Spain, June 2020.

[Slides (pptx) (pdf)]

[Lightning Talk Slides (pptx) (pdf)]

[Talk Video (20 minutes)]

[Lightning Talk Video (3 minutes)]

CLR-DRAM: A Low-Cost DRAM Architecture Enabling Dynamic Capacity-Latency Trade-Off

Haocong Luo§† Taha Shahroodi§ Hasan Hassan§ Minesh Patel§ A. Giray Yağlıkçı§ Lois Orosa§ Jisung Park§ Onur Mutlu§

§ETH Zürich †ShanghaiTech University

SALP: Reducing DRAM Bank Conflict Impact

Kim, Seshadri, Lee, Liu, Mutlu

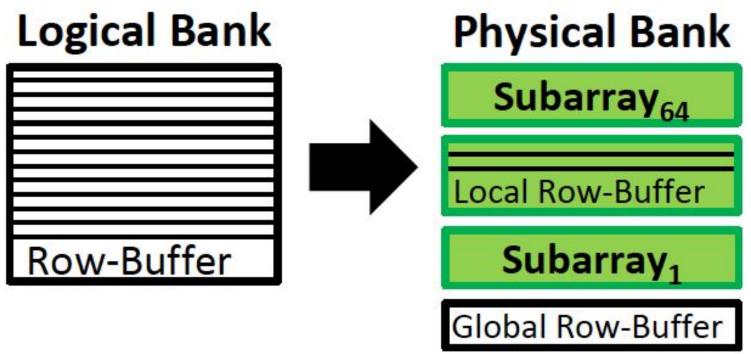
<u>A Case for Exploiting Subarray-Level Parallelism</u>

(SALP) in DRAM

ISCA 2012.

SALP: Problem, Goal, Observations

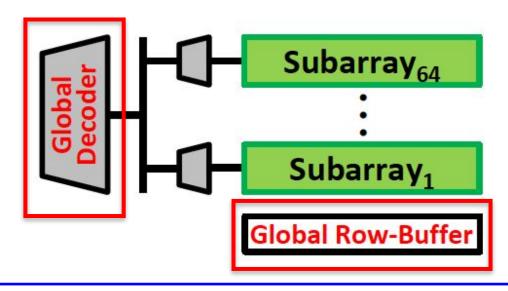
- Problem: Bank conflicts are costly for performance and energy
 - serialized requests, wasted energy (thrashing of row buffer, busy wait)
- Goal: Reduce bank conflicts without adding more banks (low cost)
- Observation 1: A DRAM bank is divided into subarrays and each subarray has its own local row buffer





SALP: Key Ideas

- Observation 2: Subarrays are mostly independent
 - Except when sharing global structures to reduce cost



Key Idea of SALP: Minimally reduce sharing of global structures

Reduce the sharing of ...

Global decoder

Enables almost parallel access to subarrays

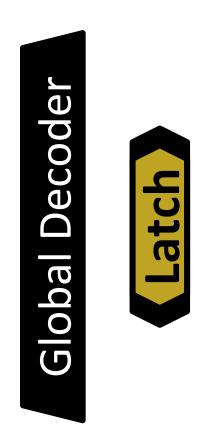
Global row buffer

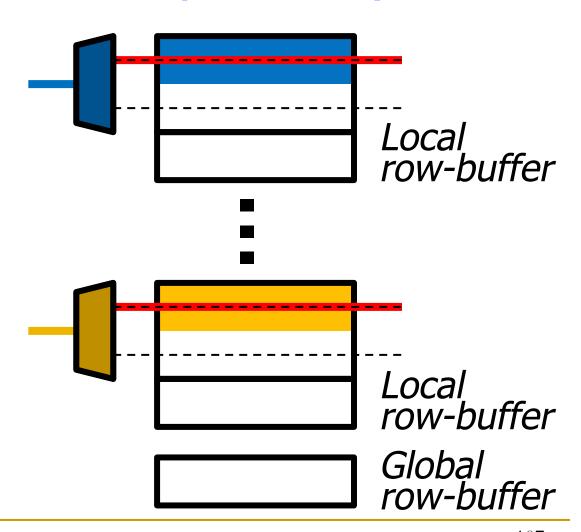
Utilizes multiple local row buffers

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SALP: Reduce Sharing of Global Decoder

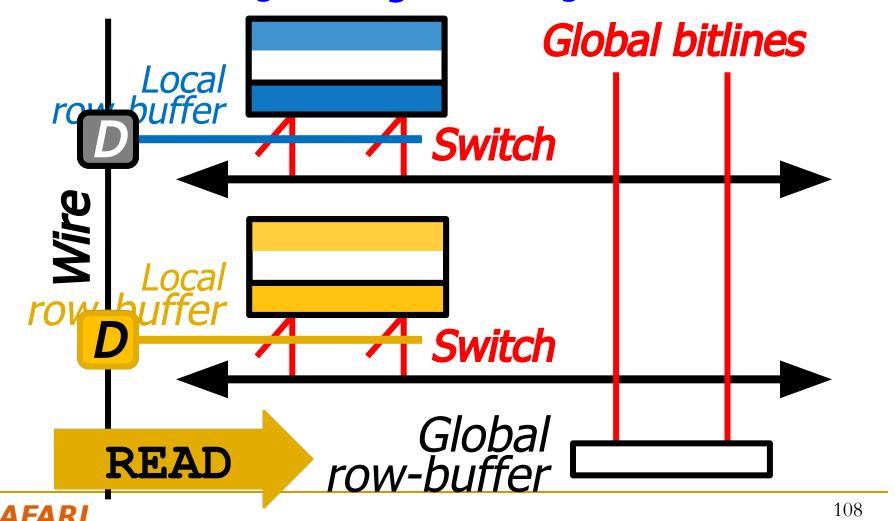
Instead of a global latch, have per-subarray latches



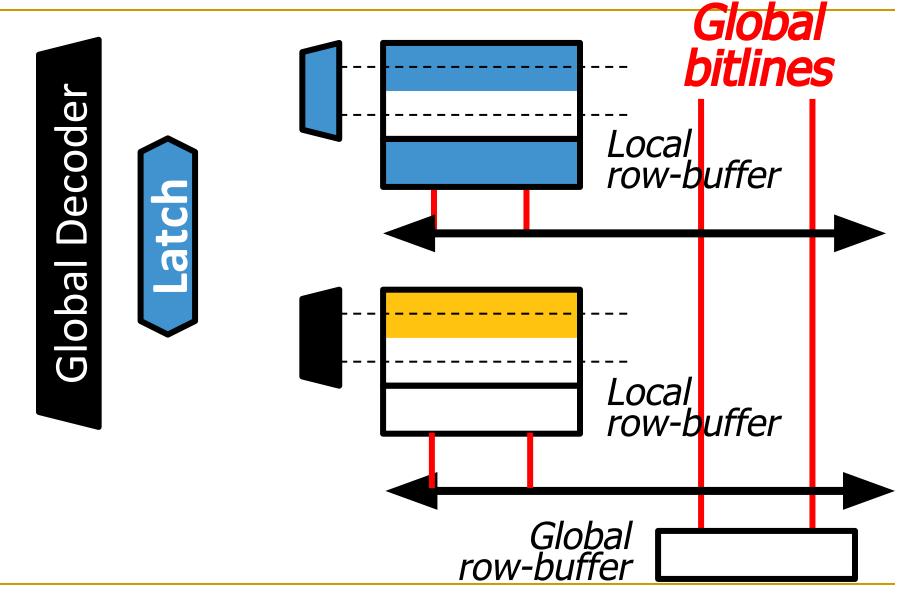


SALP: Reduce Sharing of Global Row-Buffer

Selectively connect local row-buffers to global row-buffer using a *Designated* single-bit latch



SALP: Baseline Bank Organization



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SALP: Proposed Bank Organization

bitlines **Global Decoder** Local row-buffer Local row-buffer Global row-buffer

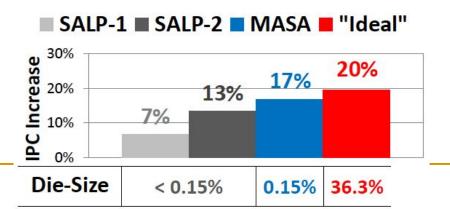
Overhead of SALP in DRAM chip: 0.15%

- 1. Global latch □ per-subarray local latches
- 2. Designated bit latches and wire to selectively enable a subarray

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SALP: Results

- Wide variety of systems with different #channels, banks, ranks, subarrays
- Server, streaming, random-access, SPEC workloads
- Dynamic DRAM energy reduction: 19%
 - DRAM row hit rate improvement: 13%
- System performance improvement: 17%
 - Within 3% of ideal (all independent banks)
- DRAM die area overhead: 0.15%
 - vs. 36% overhead of independent banks



 Yoongu Kim, Vivek Seshadri, Donghyuk Lee, Jamie Liu, and Onur Mutlu,

"A Case for Exploiting Subarray-Level Parallelism (SALP) in DRAM"

Proceedings of the <u>39th International Symposium on</u> <u>Computer Architecture</u> (**ISCA**), Portland, OR, June 2012. <u>Slides (pptx)</u>

A Case for Exploiting Subarray-Level Parallelism (SALP) in DRAM

Yoongu Kim Vivek Seshadri Donghyuk Lee Jamie Liu Onur Mutlu Carnegie Mellon University

DRAM Process Scaling Challenges

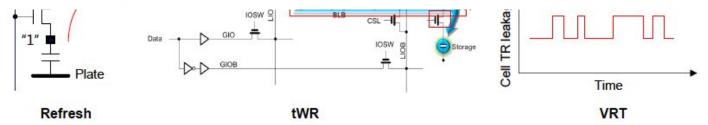
Refresh

Difficult to build high-aspect ratio cell capacitors decreasing cell capacitance.
 THE MEMORY FORUM 2014

Co-Architecting Controllers and DRAM to Enhance DRAM Process Scaling

Uksong Kang, Hak-soo Yu, Churoo Park, *Hongzhong Zheng, **John Halbert, **Kuljit Bains, SeongJin Jang, and Joo Sun Choi

Samsung Electronics, Hwasung, Korea / *Samsung Electronics, San Jose / **Intel









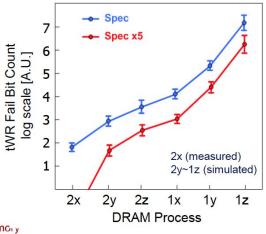
Sub-array Level Parallelism with tWR Relaxation

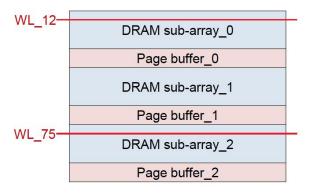
tWR relaxation

- Relaxing tWR results in DRAM yield improvement but can degrade performance requiring new compensating features
- By increasing tWR 5X (from 15ns to 75ns), fail bit counts are expected to reduce by 1 to 2 orders of magnitudes

❖ Sub-array level parallelism (SALP)

- Allows a page in another sub-array in the same bank to be opened in parallel with the currently activated sub-array
- Results in performance gain by increasing the row access parallelism within a bank
 ⇒ Used to compensate for the performance loss caused by tWR relaxation





Single bank with multiple sub-arrays

SAMSUNG

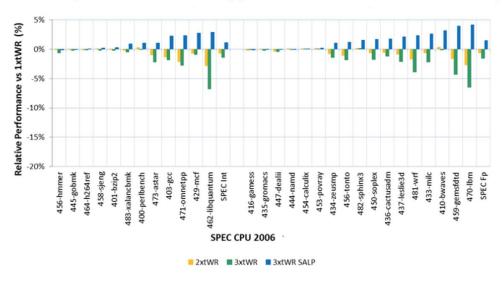


The Memo_{i y} Forum

SAFARI

Performance Impact of SALP and tWR relaxation

- Performance simulations run for various workloads when tWR is relaxed by 2X and 3X, and when SALP is applied with 2 sub-banks
- ❖ Results show that performance is reduced by ~5% and ~2% in average if tWR is relaxed by 3X and 2X, respectively
- ❖ Results also show that performance is compensated, and even improved to up to ~3% in average when SALP is applied, even with tWR relaxed by 3X





SAMSUNG



SAFARI

Why the Long Memory Latency?

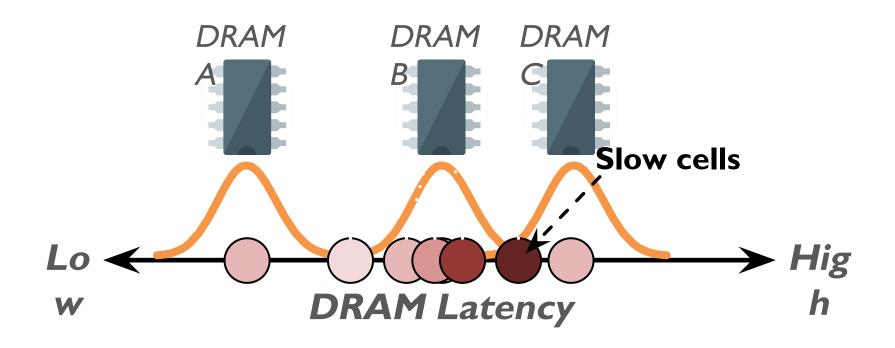
- Reason 1: Design of DRAM Micro-architecture
 - Goal: Maximize capacity/area, not minimize latency
- Reason 2: "One size fits all" approach to latency specification
 - Same latency parameters for all temperatures
 - Same latency parameters for all DRAM chips
 - Same latency parameters for all parts of a DRAM chip
 - Same latency parameters for all supply voltage levels
 - Same latency parameters for all application data
 - **...**

Tackling the Fixed Latency Mindset

- Reliable operation latency is actually very heterogeneous
 - Across temperatures, chips, parts of a chip, voltage levels, ...
- Idea: Dynamically find out and use the lowest latency one can reliably access a memory location with
 - Adaptive-Latency DRAM [HPCA 2015]
 - Flexible-Latency DRAM [SIGMETRICS 2016]
 - Design-Induced Variation-Aware DRAM [SIGMETRICS 2017]
 - Voltron [SIGMETRICS 2017]
 - DRAM Latency PUF [HPCA 2018]
 - Solar DRAM [ICCD 2018]
 - DRAM Latency True Random Number Generator [HPCA 2019]
- We would like to find sources of latency heterogeneity and exploit them to minimize latency (or create other benefits)

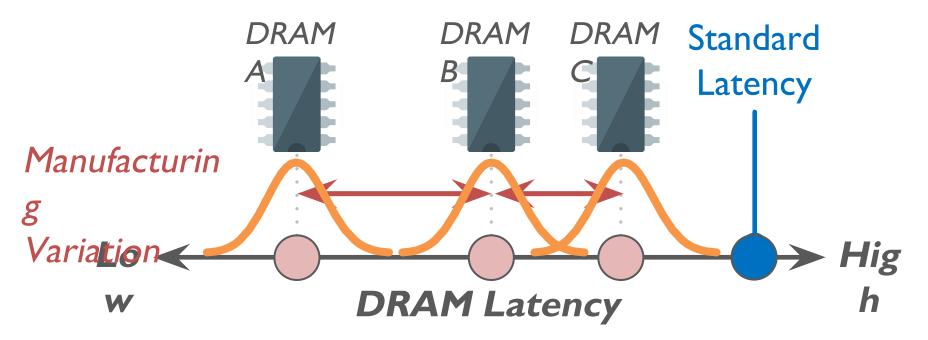
Latency Variation in Memory Chips

Heterogeneous manufacturing & operating conditions → latency variation in timing parameters



Why is Latency High?

- DRAM latency: Delay as specified in DRAM standards
 - Doesn't reflect true DRAM device latency
- Imperfect manufacturing process → latency variation
- High standard latency chosen to increase yield



What Causes the Long Memory Latency?

Conservative timing margins!

- DRAM timing parameters are set to cover the worst case
- Worst-case temperatures
 - 85 degrees vs. common-case
 - to enable a wide range of operating conditions
- Worst-case devices
 - DRAM cell with smallest charge across any acceptable device
 - to tolerate process variation at acceptable yield
- This leads to large timing margins for the common case

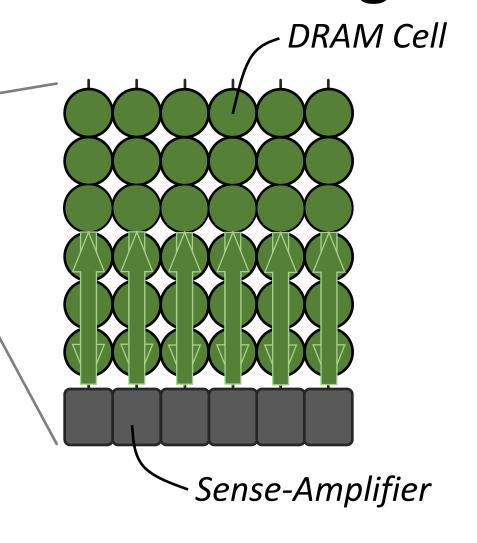
Understanding and Exploiting Variation in DRAM Latency

DRAM Stores Data as Charge

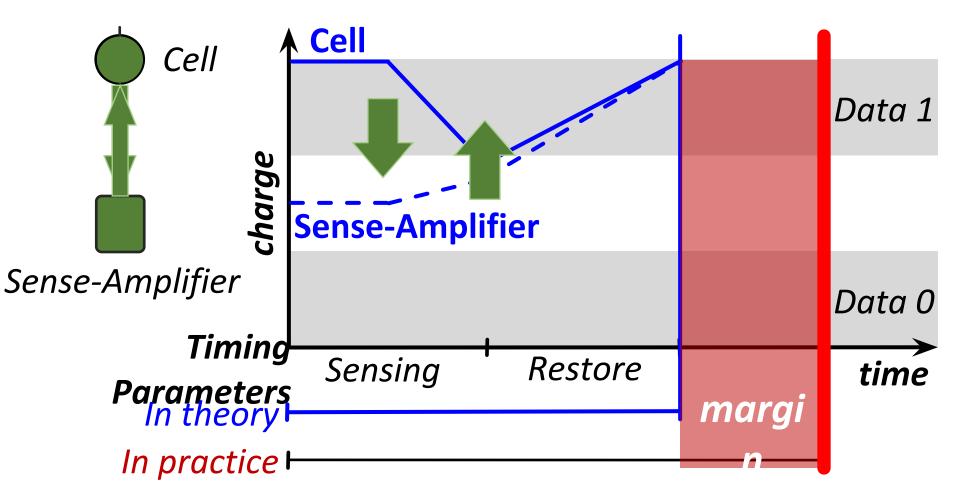


Three steps of charge movement

- 1. Sensing
- 2. Restore
- 3. Precharge



DRAM Charge over Time



Why does DRAM need the extra timing margin?

Margin

1. Process Variation

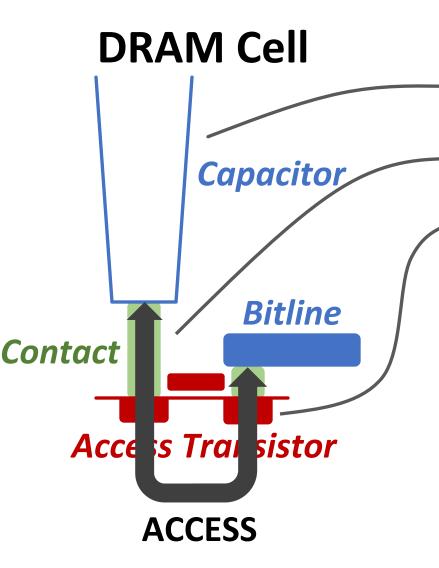
- DRAM cells are not equal
- Leads to extra timing margin for a cell that can store a large amount of charge

2. Temperature Dependence

DRAM Cells are Not Equal Real Smallest Cell

Same Charge Different Charge Same Charge Different Charge Large Nariation in Green Large Variation in access latency

Process Variation



- Cell Capacitance
- Contact Resistance
- **3** Transistor Performance

Small cell can store small charge

- Small cell capacitance
- High contact resistance
- Slow access transistor

☐ High access latency 126

Margin

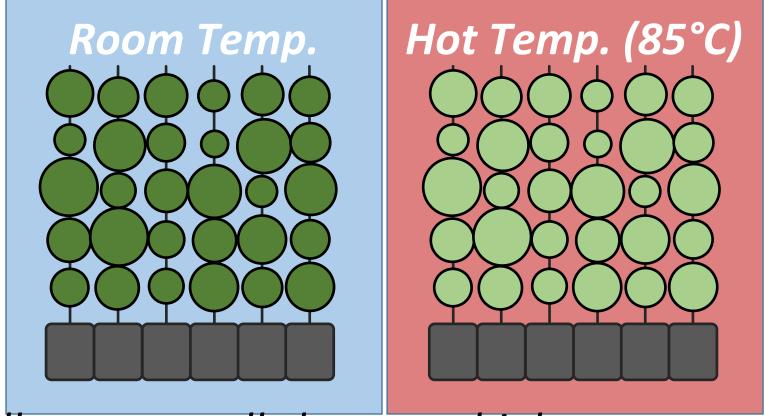
1. Process Variation

- DRAM cells are not equal
- Leads to extra timing margin for a cell that can store a large amount of charge

2. Temperature Dependence

- DRAM leaks more charge at higher temperature
- Leads to extra timing margin for cells that operate at low temperature.

Temperature



Cells storessing high temperature and large charge at low temperature

□ Large variation in access latency



DRAM Timing Parameters

- DRAM timing parameters are dictated by the worst-case
 - The smallest cell with the smallest charge <u>in</u>
 <u>all DRAM products</u>
 - Operating at the highest temperature

Large timing margin for the common-case

Adaptive-Latency DRAM [HPCA 2015]

- Idea: Optimize DRAM timing for the common case
 - Current temperature
 - Current DRAM module
- Why would this reduce latency?
 - A DRAM cell can store much more charge in the common case (low temperature, strong cell) than in the worst case
 - More charge in a DRAM cell
 - ☐ Faster sensing, charge restoration, precharging
 - ☐ Faster access (read, write, refresh, ...)

Extra Charge Reduced Latency

1. Sensing

Sense cells with extra charge faster

□ Lower sensing latency

2. Restore

No need to fully restore cells with extra charge

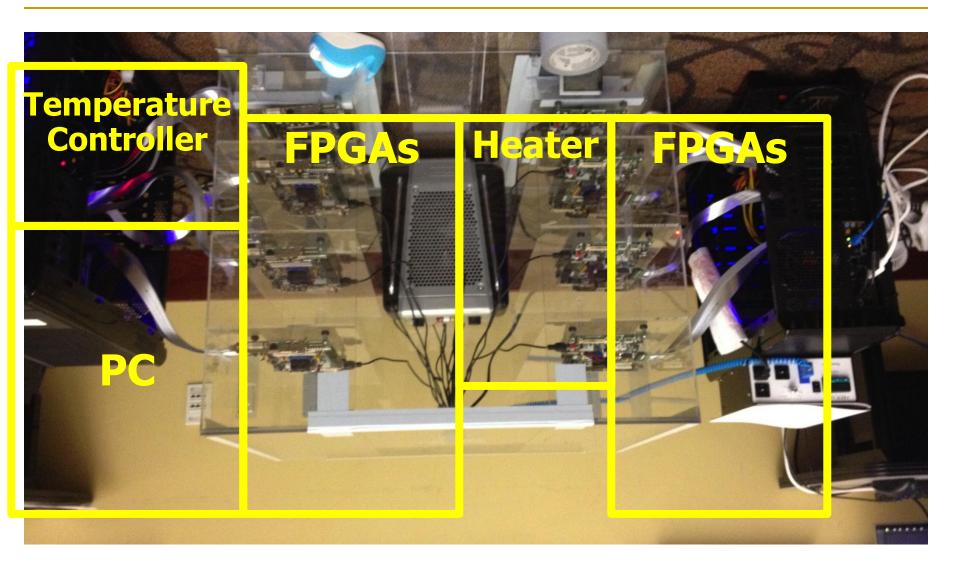
□ Lower restoration latency

3. Precharge

No need to fully precharge bitlines for **cells with extra charge**

□ Lower precharge latency

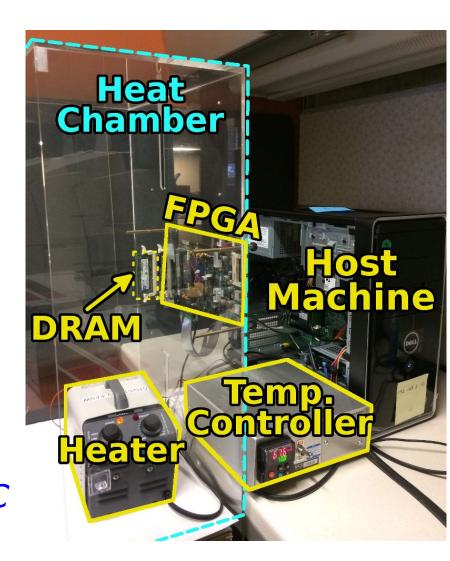
DRAM Characterization Infrastructure



DRAM Characterization Infrastructure

 Hasan Hassan et al., <u>SoftMC: A</u>
 Flexible and Practical
 Open-Source Infrastructure
 for Enabling Experimental
 DRAM Studies, HPCA 2017.

- Flexible
- Easy to Use (C++ API)
- Open-source github.com/CMU-SAFARI/SoftMC



SoftMC: Open Source DRAM Infrastructure

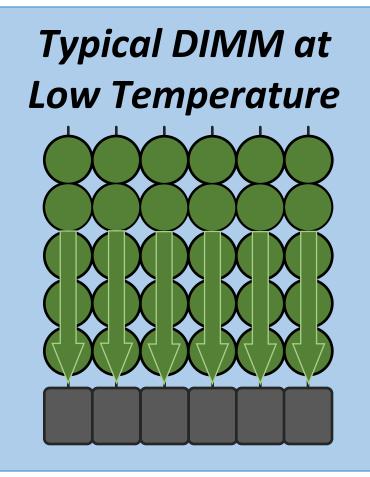
https://github.com/CMU-SAFARI/SoftMC

SoftMC: A Flexible and Practical Open-Source Infrastructure for Enabling Experimental DRAM Studies

```
 Hasan Hassan Nandita Vijaykumar Samira Khan Saugata Ghose Kevin Chang Gennady Pekhimenko Donghyuk Lee^{6,3} Oguz Ergin Onur Mutlu Onur Mutlu
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<sup>1</sup>ETH Zürich <sup>2</sup>TOBB University of Economics & Technology <sup>3</sup>Carnegie Mellon University <sup>4</sup>University of Virginia <sup>5</sup>Microsoft Research <sup>6</sup>NVIDIA Research
```

Observation 1. Faster Sensing



More Charge

Strong Charge Flow

Faster Sensing

115 DIMM Characterization

Timing

(tRCD)

17% ↓

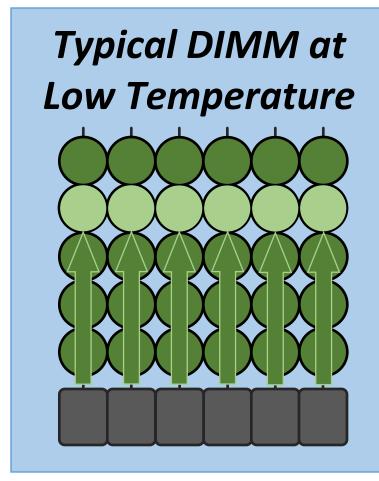
No Errors

Typical DIMM at Low Temperature

□ More charge □ Faster sensing



Observation 2. Reducing Restore Time



Less Leakage

Extra Charge

No Need to Fully Restore Charge

115 DIMM Characterization

Read (tRAS)

37% ↓

Write (tWR)

54% ↓

No Errors

Typical DIMM at lower temperature

□ More charge □ Restore time reduction



AL-DRAM

- Key idea
 - Optimize DRAM timing parameters online
- Two components
 - DRAM manufacturer provides multiple sets of reliable DRAM timing parameters at different temperatures for each DIMM
 - System monitors DRAM temperature & uses appropriate DRAM timing parameters



DRAM Temperature

- DRAM temperature measurement
 - Server cluster: Operates at under 34°C
 - Desktop: Operates at under 50°C
 - DRAM standard optimized for 85°C

DRAM operates at low temperatures in the common-case

- Previous works Maintain low DRAM temperature
 - David+ ICAC 2011
 - Liu+ ISCA 2007
 - Zhu+ ITHERM 2008

Latency Reduction Summary of 115 DIMMs

- Latency reduction for read & write (55°C)
 - Read Latency: 32.7%
 - Write Latency: **55.1%**
- Latency reduction for each timing parameter (55°C)
 - Sensing: 17.3%
 - Restore: 37.3% (read), 54.8% (write)
 - Precharge: 35.2%



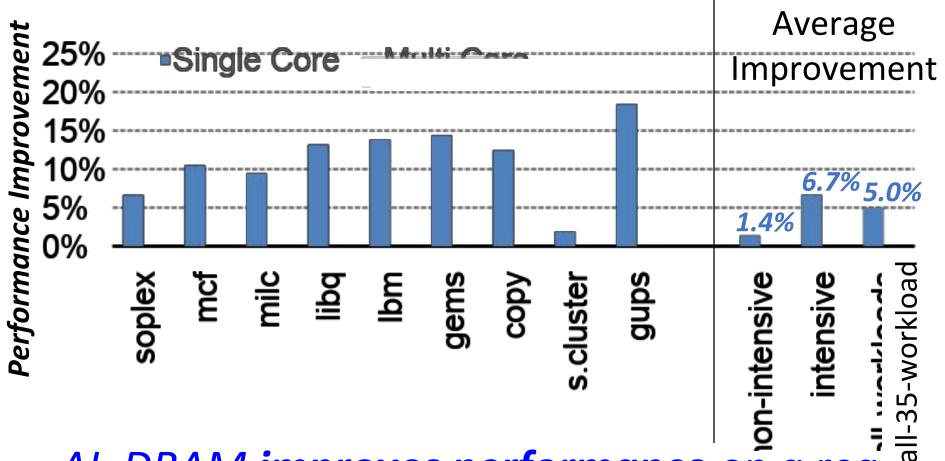
AL-DRAM: Real System Evaluation

System

- CPU: AMD 4386 (8 Cores, 3.1GHz, 8MB LLC)

D18F2x200_dct[0]_mp[1:0] DDR3 DRAM Timing 0		
Reset: 0F05_0505h. See 2.9.3 [DCT Configuration Registers].		
E .	80	
Bits	Description	
31:30	Reserved.	
29:24	1.00	re strobe. Read-write. BIOS: See 2.9.7.5 [SPD ROM-Based Configuration]. Specifies me in memory clock cycles from an activate command to a precharge command, both o select bank. Description Reserved Tras> clocks Reserved
23:21	Reserved.	
20:16	Trp: row precharge time . Read-write. BIOS: See 2.9.7.5 [SPD ROM-Based Configuration]. Specifies the minimum time in memory clock cycles from a precharge command to an activate command or auto refresh command, both to the same bank.	

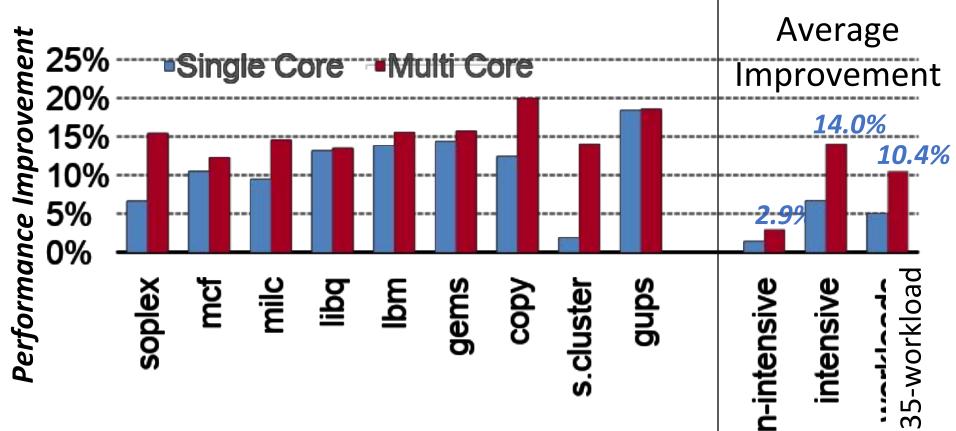
AL-DRAM: Single-Core Evaluation



AL-DRAM improves performance on a real

system

AL-DRAM: Multi-Core Evaluation



AL-DRAM provides higher performance for multi-programmed & multi-threaded workloads

SAFARI

Reducing Latency Also Reduces Energy

- AL-DRAM reduces DRAM power consumption by 5.8%
- Major reason: reduction in row activation time

AL-DRAM: Advantages & Disadvantages

Advantages

- + Simple mechanism to reduce latency
- + Significant system performance and energy benefits
 - + Benefits higher at low temperature
- + Low cost, low complexity

Disadvantages

 Need to determine reliable operating latencies for different temperatures and different DIMMs □ higher testing cost (might not be that difficult for low temperatures)

More on AL-DRAM

 Donghyuk Lee, Yoongu Kim, Gennady Pekhimenko, Samira Khan, Vivek Seshadri, Kevin Chang, and Onur Mutlu,
 "Adaptive-Latency DRAM: Optimizing DRAM Timing for the Common-Case"

Proceedings of the <u>21st International Symposium on</u> <u>High-Performance Computer Architecture</u> (**HPCA**), Bay Area, CA, February 2015.

[Slides (pptx) (pdf)] [Full data sets]

Adaptive-Latency DRAM: Optimizing DRAM Timing for the Common-Case

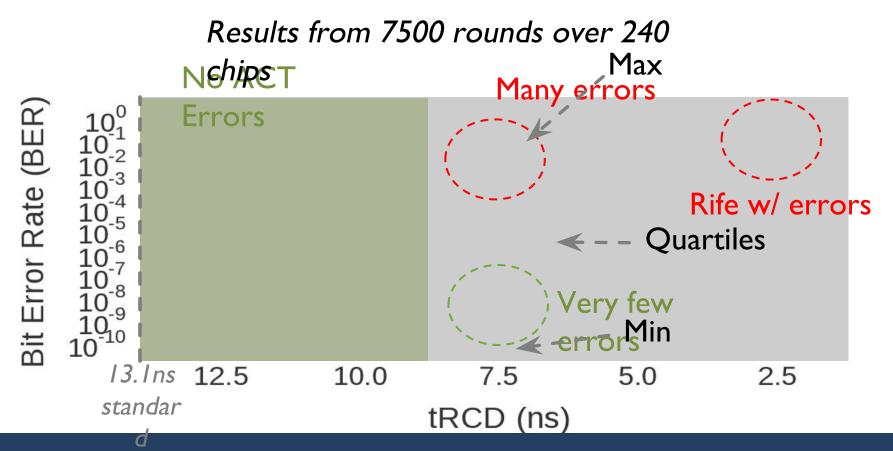
Donghyuk Lee Yoongu Kim Gennady Pekhimenko Samira Khan Vivek Seshadri Kevin Chang Onur Mutlu Carnegie Mellon University

Different Types of Latency Variation

- AL-DRAM exploits latency variation
 - Across time (different temperatures)
 - Across chips

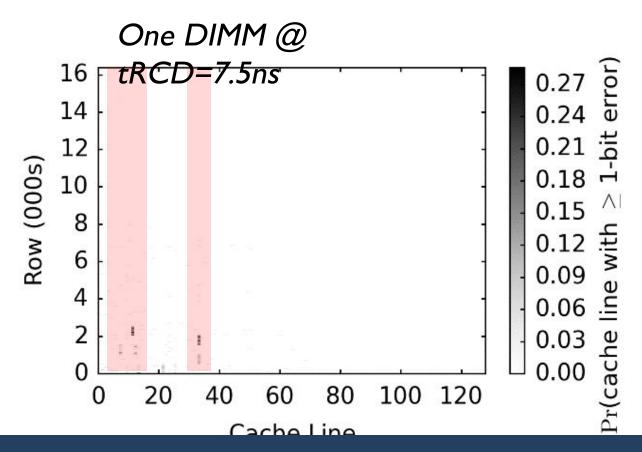
- Is there also latency variation within a chip?
 - Across different parts of a chip

Variation in Activation Errors



Modern DRAM chips exhibit significant variation in activation latency

Spatial Locality of Activation Errors

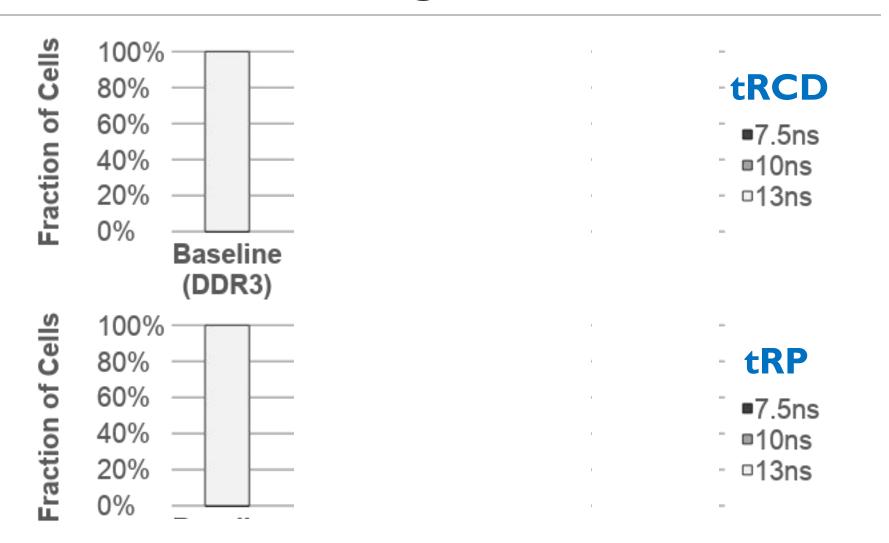


Activation errors are concentrated at certain columns of cells

Mechanism to Reduce DRAM Latency

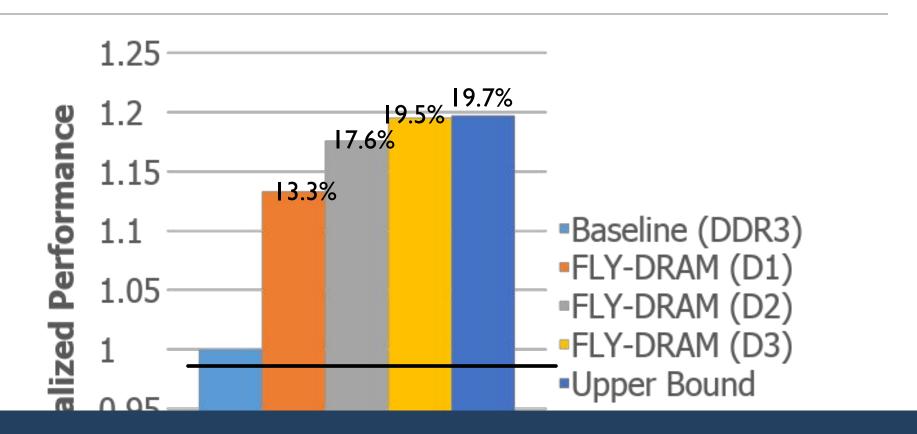
- Observation: DRAM timing errors (slow DRAM cells) are concentrated on certain regions
- Flexible-LatencY (FLY) DRAM
 - A software-transparent design that reduces latency
- Key idea:
 - 1) Divide memory into regions of different latencies
 - 2) Memory controller: Use lower latency for regions without slow cells; higher latency for other regions

FLY-DRAM Configurations



Chang+, "<u>Understanding Latency Variation in Modern DRAM Chips: Experimental</u> <u>Characterization, Analysis, and Optimization"</u>," SIGMETRICS 2016.

Results



FLY-DRAM improves performance by exploiting spatial latency variation in DRAM

Chang+, "<u>Understanding Latency Variation in Modern DRAM Chips: Experimental</u> <u>Characterization, Analysis, and Optimization"</u>," SIGMETRICS 2016.

FLY-DRAM: Advantages & Disadvantages

Advantages

- + Reduces latency significantly
 - + Exploits significant within-chip latency variation

Disadvantages

- Need to determine reliable operating latencies for different parts of a chip □ higher testing cost
 - Slightly more complicated controller

Analysis of Latency Variation in DRAM Chips

Kevin Chang, Abhijith Kashyap, Hasan Hassan, Samira Khan, Kevin Hsieh, Donghyuk Lee, Saugata Ghose, Gennady Pekhimenko, Tianshi Li, and Onur Mutlu,

"Understanding Latency Variation in Modern DRAM Chips: **Experimental Characterization, Analysis, and Optimization**" Proceedings of the <u>ACM International Conference on Measurement and</u> Modeling of Computer Systems (SIGMETRICS), Antibes Juan-Les-Pins, France, June 2016.

[Slides (pptx) (pdf)]

Source Code

Understanding Latency Variation in Modern DRAM Chips: Experimental Characterization, Analysis, and Optimization

Kevin K. Chang¹ Abhijith Kashyap¹ Hasan Hassan^{1,2} Saugata Ghose¹ Kevin Hsieh¹ Donghyuk Lee¹ Tianshi Li^{1,3} Gennady Pekhimenko¹ Samira Khan⁴ Onur Mutlu^{5,1}

¹Carnegie Mellon University ²TOBB ETÜ ³Peking University ⁴University of Virginia ⁵ETH Zürich SAFARI

Putting It All Together: Solar-DRAM

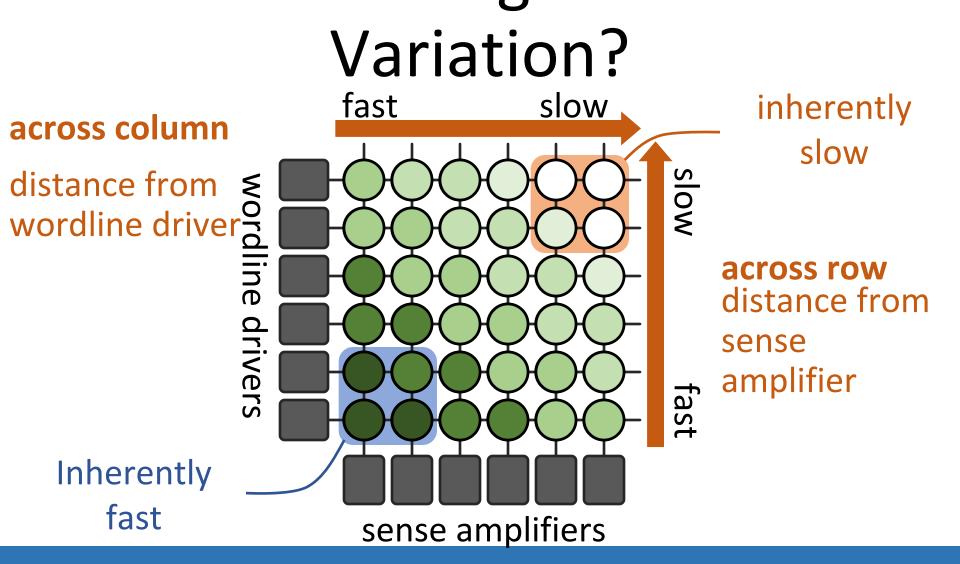
Solar-DRAM: Putting It Together

Jeremie S. Kim, Minesh Patel, Hasan Hassan, and Onur Mutlu, "Solar-DRAM: Reducing DRAM Access Latency by Exploiting the Variation in Local Bitlines"
 Proceedings of the 36th IEEE International Conference on Computer Design (ICCD), Orlando, FL, USA, October 2018.
 [Slides (pptx) (pdf)]
 [Talk Video (16 minutes)]

Solar-DRAM: Reducing DRAM Access Latency by Exploiting the Variation in Local Bitlines

Jeremie S. Kim^{‡§} Minesh Patel[§] Hasan Hassan[§] Onur Mutlu^{§‡}
[‡]Carnegie Mellon University [§]ETH Zürich

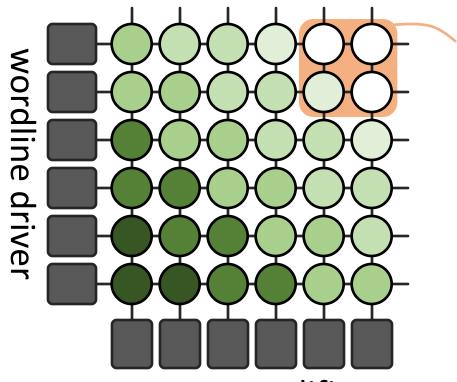
Why Is There Spatial Latency Variation Within a Chip?



Systematic variation in cell access times caused by the **physical organization** of DRAM

DIVA Online **Profiling**

Design-Induced-Variation-Aware



inherently slow

Profile *only slow regions* to determine min.

□ **Dynamic** & **low cost** Patency optimization

DIVA Online **Profiling**

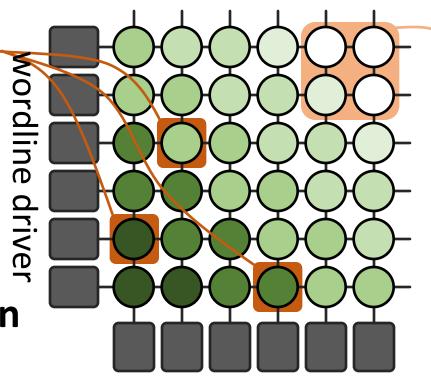
Design-Induced-Variation-Aware

slow cells

process variation random error



error-correctin g code



inherently

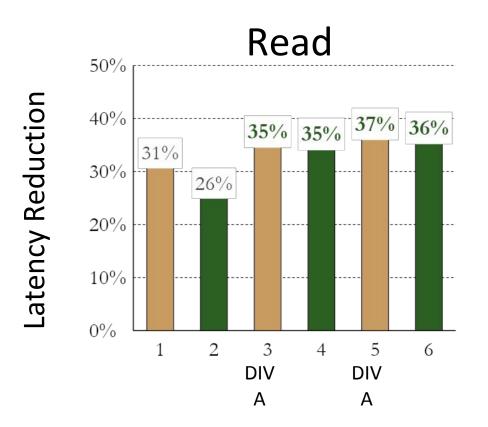
design-induced variation localized error

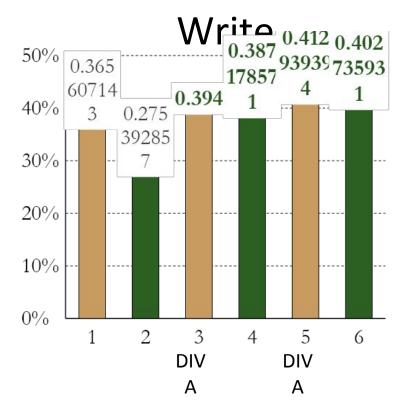


Combine error-correcting codes & online

☐ Reliably reduce BRAM latency

DIVA-DRAM Reduces Latency





DIVA-DRAM *reduces latency more aggressively* and uses ECC to correct random slow cells

DIVA-DRAM: Advantages & Disadvantages

Advantages

- ++ Automatically finds the lowest reliable operating latency at system runtime (lower production-time testing cost)
 - + Reduces latency more than prior methods (w/ ECC)
 - + Reduces latency at high temperatures as well

Disadvantages

- Requires knowledge of inherently-slow regions
- Requires ECC (Error Correcting Codes)
- Imposes overhead during runtime profiling

Design-Induced Latency Variation in DRAM

 Donghyuk Lee, Samira Khan, Lavanya Subramanian, Saugata Ghose, Rachata Ausavarungnirun, Gennady Pekhimenko, Vivek Seshadri, and Onur Mutlu,

"Design-Induced Latency Variation in Modern DRAM Chips: Characterization, Analysis, and Latency Reduction Mechanisms" Proceedings of the <u>ACM International Conference on Measurement and Modeling of Computer Systems</u> (SIGMETRICS), Urbana-Champaign, IL, USA, June 2017.

Design-Induced Latency Variation in Modern DRAM Chips: Characterization, Analysis, and Latency Reduction Mechanisms

Donghyuk Lee, NVIDIA and Carnegie Mellon University
Samira Khan, University of Virginia
Lavanya Subramanian, Saugata Ghose, Rachata Ausavarungnirun, Carnegie Mellon University
Gennady Pekhimenko, Vivek Seshadri, Microsoft Research
Onur Mutlu, ETH Zürich and Carnegie Mellon University

Understanding & Exploiting the Voltage-Latency-Reliability Relationship

Analysis of Latency-Voltage in DRAM Chips

 Kevin Chang, A. Giray Yaglikci, Saugata Ghose, Aditya Agrawal, Niladrish Chatterjee, Abhijith Kashyap, Donghyuk Lee, Mike O'Connor, Hasan Hassan, and <u>Onur Mutlu</u>,

"Understanding Reduced-Voltage Operation in Modern DRAM Devices: Experimental Characterization, Analysis, and Mechanisms"

Proceedings of the <u>ACM International Conference on Measurement and Modeling of Computer Systems</u> (**SIGMETRICS**), Urbana-Champaign, IL, USA, June 2017.

Understanding Reduced-Voltage Operation in Modern DRAM Chips: Characterization, Analysis, and Mechanisms

Kevin K. Chang[†] Abdullah Giray Yağlıkçı[†] Saugata Ghose[†] Aditya Agrawal[¶] Niladrish Chatterjee[¶] Abhijith Kashyap[†] Donghyuk Lee[¶] Mike O'Connor^{¶,‡} Hasan Hassan[§] Onur Mutlu^{§,†}
[†]Carnegie Mellon University [¶]NVIDIA [‡]The University of Texas at Austin [§]ETH Zürich

Reducing Memory Latency to Support Security Primitives

Using Memory for Security

- Generating True Random Numbers (using DRAM)
 - Kim et al., HPCA 2019

- Evaluating Physically Unclonable Functions (using DRAM)
 - Kim et al., HPCA 2018

- Quickly Destroying In-Memory Data (using DRAM)
 - Orosa et al., arxiv 2019

DRAM Latency PUFs

Jeremie S. Kim, Minesh Patel, Hasan Hassan, and Onur Mutlu,
 "The DRAM Latency PUF: Quickly Evaluating Physical Unclonable
 Functions by Exploiting the Latency-Reliability Tradeoff in
 Modern DRAM Devices"

Proceedings of the <u>24th International Symposium on High-Performance</u> <u>Computer Architecture</u> (**HPCA**), Vienna, Austria, February 2018. [<u>Lightning Talk Video</u>]

[Slides (pptx) (pdf)] [Lightning Session Slides (pptx) (pdf)]

The DRAM Latency PUF:

Quickly Evaluating Physical Unclonable Functions by Exploiting the Latency-Reliability Tradeoff in Modern Commodity DRAM Devices

Jeremie S. Kim^{†§} Minesh Patel[§] Hasan Hassan[§] Onur Mutlu^{§†}

[†]Carnegie Mellon University [§]ETH Zürich

DRAM Latency True Random Number Generator

Jeremie S. Kim, Minesh Patel, Hasan Hassan, Lois Orosa, and Onur Mutlu, "D-RaNGe: Using Commodity DRAM Devices to Generate True Random Numbers with Low Latency and High Throughput" Proceedings of the <u>25th International Symposium on High-Performance</u> Computer Architecture (HPCA), Washington, DC, USA, February 2019.

D-RaNGe: Using Commodity DRAM Devices to Generate True Random Numbers with Low Latency and High Throughput

Jeremie S. Kim^{‡§} Minesh Patel[§] Hasan Hassan[§] Lois Orosa[§] Onur Mutlu^{§‡} [‡]Carnegie Mellon University [§]ETH Zürich

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Reducing Refresh Latency

Reducing Refresh Latency

Anup Das, Hasan Hassan, and Onur Mutlu,
 "VRL-DRAM: Improving DRAM Performance via
 Variable Refresh Latency"
 Proceedings of the <u>55th Design Automation</u>
 Conference (DAC), San Francisco, CA, USA, June 2018.

VRL-DRAM: Improving DRAM Performance via Variable Refresh Latency

Anup Das
Drexel University
Philadelphia, PA, USA
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Hasan Hassan ETH Zürich Zürich, Switzerland hhasan@ethz.ch Onur Mutlu
ETH Zürich
Zürich, Switzerland
omutlu@gmail.com

Reducing Memory Latency by Exploiting Memory Access Patterns

ChargeCache: Exploiting Access Patterns

 Hasan Hassan, Gennady Pekhimenko, Nandita Vijaykumar, Vivek Seshadri, Donghyuk Lee, Oguz Ergin, and Onur Mutlu, "ChargeCache: Reducing DRAM Latency by Exploiting Row Access Locality"

Proceedings of the <u>22nd International Symposium on</u>
<u>High-Performance Computer Architecture</u> (**HPCA**), Barcelona, Spain,
March 2016.

[Slides (pptx) (pdf)]
[Source Code]

ChargeCache: Reducing DRAM Latency by Exploiting Row Access Locality

Hasan Hassan^{†*}, Gennady Pekhimenko[†], Nandita Vijaykumar[†] Vivek Seshadri[†], Donghyuk Lee[†], Oguz Ergin^{*}, Onur Mutlu[†]

Partial Restoration of Cell Charge

 Yaohua Wang, Arash Tavakkol, Lois Orosa, Saugata Ghose, Nika Mansouri Ghiasi, Minesh Patel, Jeremie S. Kim, Hasan Hassan, Mohammad Sadrosadati, and Onur Mutlu,

"Reducing DRAM Latency via Charge-Level-Aware Look-Ahead Partial Restoration"

Proceedings of the <u>51st International Symposium on</u> <u>Microarchitecture</u> (**MICRO**), Fukuoka, Japan, October 2018.

Reducing DRAM Latency via Charge-Level-Aware Look-Ahead Partial Restoration

```
Yaohua Wang<sup>†§</sup> Arash Tavakkol<sup>†</sup> Lois Orosa<sup>†*</sup> Saugata Ghose<sup>‡</sup> Nika Mansouri Ghiasi<sup>†</sup> Minesh Patel<sup>†</sup> Jeremie S. Kim<sup>‡†</sup> Hasan Hassan<sup>†</sup> Mohammad Sadrosadati<sup>†</sup> Onur Mutlu<sup>†‡</sup>
```

†ETH Zürich §National University of Defense Technology ‡Carnegie Mellon University *University of Campinas

Parallelizing Refreshes and Accesses

 Kevin Chang, Donghyuk Lee, Zeshan Chishti, Alaa Alameldeen, Chris Wilkerson, Yoongu Kim, and Onur Mutlu,

"Improving DRAM Performance by Parallelizing Refreshes with Accesses"

Proceedings of the <u>20th International Symposium on High-Performance</u> <u>Computer Architecture</u> (**HPCA**), Orlando, FL, February 2014. [<u>Summary</u>] [<u>Slides (pptx) (pdf)</u>]

Reducing Performance Impact of DRAM Refresh by Parallelizing Refreshes with Accesses

Kevin Kai-Wei Chang Donghyuk Lee Zeshan Chishti†

Alaa R. Alameldeen† Chris Wilkerson† Yoongu Kim Onur Mutlu

Carnegie Mellon University †Intel Labs

On DRAM Power Consumption

VAMPIRE DRAM Power Model

Saugata Ghose, A. Giray Yaglikci, Raghav Gupta, Donghyuk Lee, Kais Kudrolli, William X. Liu, Hasan Hassan, Kevin K. Chang, Niladrish Chatterjee, Aditya Agrawal, Mike O'Connor, and Onur Mutlu,

"What Your DRAM Power Models Are Not Telling You: Lessons from a Detailed **Experimental Study**"

Proceedings of the <u>ACM International Conference on Measurement and Modeling of</u> <u>Computer Systems</u> (**SIGMETRICS**), Irvine, CA, USA, June 2018.

[Abstract]

[POMACS Journal Version (same content, different format)]

[Slides (pptx) (pdf)]

VAMPIRE DRAM Power Model

What Your DRAM Power Models Are Not Telling You: Lessons from a Detailed Experimental Study

Saugata Ghose[†] Abdullah Giray Yağlıkçı^{‡†} Raghav Gupta[†] Donghyuk Lee[§] Kais Kudrolli[†] William X. Liu[†] Hasan Hassan[‡] Kevin K. Chang[†] Mike O'Connor^{§¶} Onur Mutlu^{‡†} Niladrish Chatterjee[§] Aditya Agrawal[§]

[†]Carnegie Mellon University [‡]ETH Zürich [§]NVIDIA

[¶]University of Texas at Austin

Summary: Low-Latency Memory

Challenge and Opportunity for Future

Fundamentally Low Latency Computing Architectures

Summary: Tackling Long Memory Latency

- Reason 1: Design of DRAM Micro-architecture
 - Goal: Maximize capacity/area, not minimize latency
- Reason 2: "One size fits all" approach to latency specification
 - Same latency parameters for all temperatures
 - Same latency parameters for all DRAM chips (e.g., rows)
 - Same latency parameters for all parts of a DRAM chip
 - Same latency parameters for all supply voltage levels
 - Same latency parameters for all application data

We Can Reduce Memory Latency with Change of Mindset

Main Memory Needs Intelligent Controllers to Reduce Latency

Some Solution Principles (More Compact)

- Data-centric design
- All components intelligent
- Better cross-layer communication, better interfaces
- Better-than-worst-case design
- Heterogeneity
- Flexibility, adaptability

Open minds

Four Key Directions

Fundamentally Secure/Reliable/Safe Architectures

- Fundamentally Energy-Efficient Architectures
 - Memory-centric (Data-centric) Architectures

Fundamentally Low-Latency Architectures

Architectures for Genomics, Medicine, Health

Computer Architecture

Lecture 10: Low-Latency Memory

Prof. Onur Mutlu
ETH Zürich
Fall 2020
22 October 2020

We Did Not Cover The Later Slides. They Are For Your Benefit.

Solar-DRAM

Solar-DRAM: Putting It Together

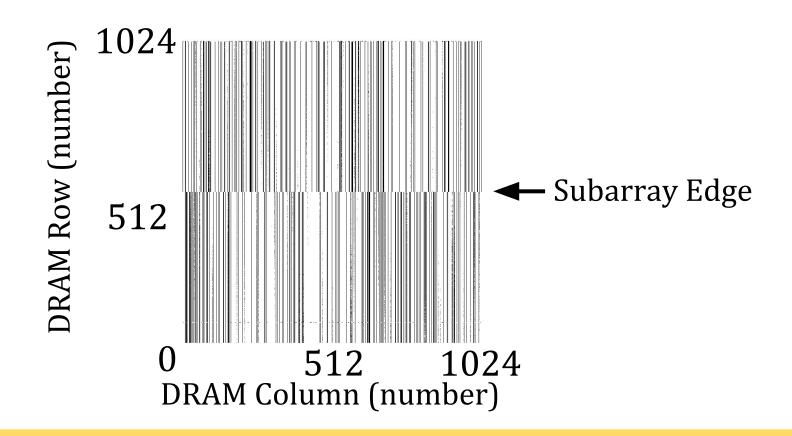
Jeremie S. Kim, Minesh Patel, Hasan Hassan, and Onur Mutlu, "Solar-DRAM: Reducing DRAM Access Latency by Exploiting the Variation in Local Bitlines"
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 [Slides (pptx) (pdf)]
 [Talk Video (16 minutes)]

Solar-DRAM: Reducing DRAM Access Latency by Exploiting the Variation in Local Bitlines

Jeremie S. Kim^{‡§} Minesh Patel[§] Hasan Hassan[§] Onur Mutlu^{§‡}
[‡]Carnegie Mellon University [§]ETH Zürich

Spatial Distribution of Failures

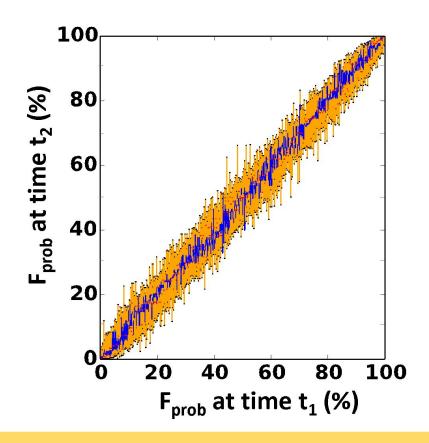
How are activation failures spatially distributed in DRAM?



Activation failures are **highly constrained** to local bitlines

Short-term Variation

Does a bitline's probability of failure change over time?



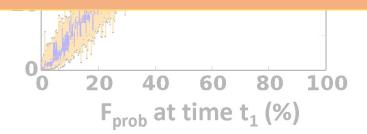
A **weak bitline** is likely to remain **weak** and a **strong bitline** is likely to remain **strong** over time

Short-term Variation

Does a bitline's probability of failure change over time?



We can rely on a **static profile** of weak bitlines to determine whether an access will cause failures

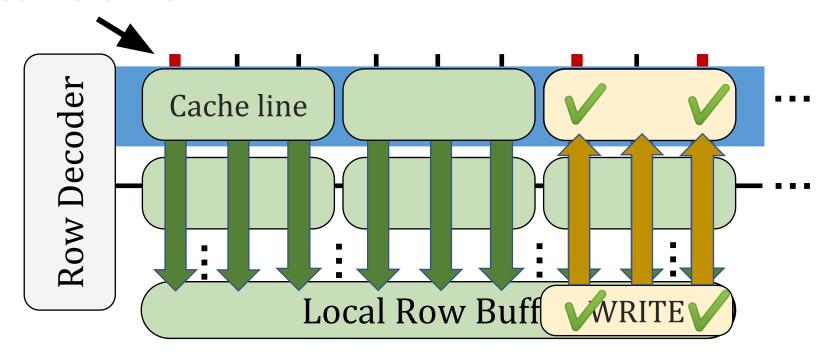


A **weak bitline** is likely to remain **weak** and a **strong bitline** is likely to remain **strong** over time

Write Operations

How are write operations affected by reduced \mathbf{t}_{RCD} ?

Weak bitline



We can reliably issue write operations with significantly reduced \mathbf{t}_{RCD} (e.g., by 77%)

Solar-DRAM

Uses a static profile of weak subarray columns

- Identifies subarray columns as weak or strong
- Obtained in a one-time profiling step

Three Components

- 1. Variable-latency cache lines (VLC)
- 2. Reordered subarray columns (RSC)
- 3. Reduced latency for writes (RLW)

Solar-DRAM

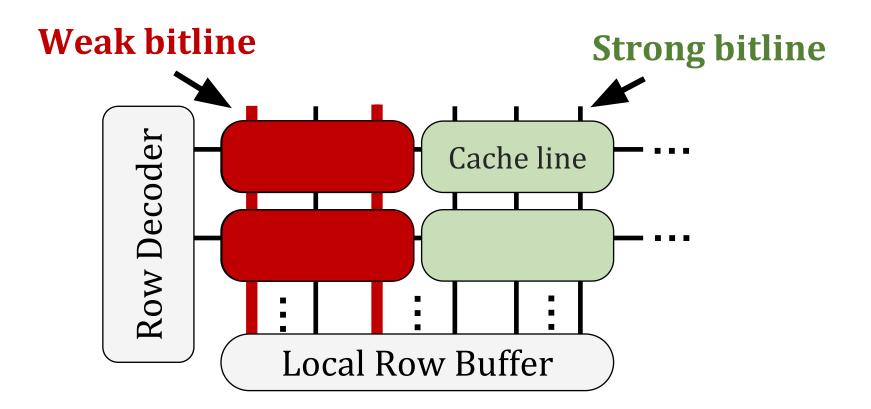
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Three Components

- 1. Variable-latency cache lines (VLC)
- 2. Reordered subarray columns (RSC)
- 3. Reduced latency for writes (RLW)

Solar-DRAM: VLC (I)



Identify cache lines comprised of **strong bitlines**Access such cache lines with a **reduced t**_{RCD}

Solar-DRAM

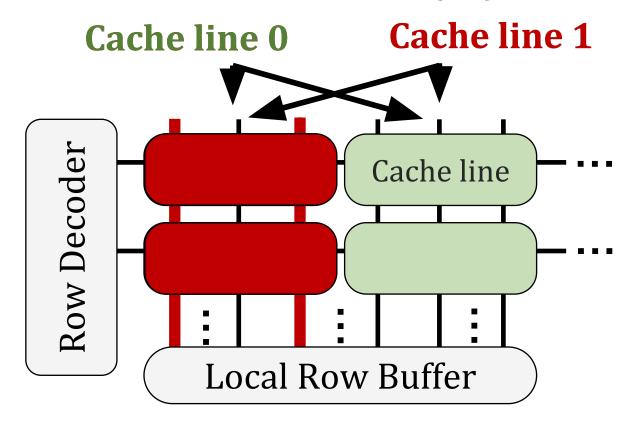
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Three Components

- 1. Variable-latency cache lines (VLC)
- 2. Reordered subarray columns (RSC)
- 3. Reduced latency for writes (RLW)

Solar-DRAM: RSC (II)



Remap cache lines across DRAM at the memory controller level so cache line 0 will likely map to a **strong** cache line

Solar-DRAM

Uses a static profile of weak subarray columns

- Identifies subarray columns as weak or strong
- Obtained in a one-time profiling step

Three Components

- 1. Variable-latency cache lines (VLC)
- 2. Reordered subarray columns (RSC)
- 3. Reduced latency for writes (RLW)

Understanding & Exploiting the Voltage-Latency-Reliability Relationship

Analysis of Latency-Voltage in DRAM Chips

 Kevin Chang, A. Giray Yaglikci, Saugata Ghose, Aditya Agrawal, Niladrish Chatterjee, Abhijith Kashyap, Donghyuk Lee, Mike O'Connor, Hasan Hassan, and <u>u</u>,

"Understanding Reduced-Voltage Operation in Modern DRAM Devices: Experimental Characterization, Analysis, and Mechanisms"

Proceedings of the <u>ACM International Conference on Measurement and Modeling of Computer Systems</u> (**SIGMETRICS**), Urbana-Champaign, IL, USA, June 2017.

Understanding Reduced-Voltage Operation in Modern DRAM Chips: Characterization, Analysis, and Mechanisms

Kevin K. Chang[†] Abdullah Giray Yağlıkçı[†] Saugata Ghose[†] Aditya Agrawal[¶] Niladrish Chatterjee[¶] Abhijith Kashyap[†] Donghyuk Lee[¶] Mike O'Connor^{¶,‡} Hasan Hassan[§] Onur Mutlu^{§,†}

[†]Carnegie Mellon University [¶]NVIDIA [‡]The University of Texas at Austin [§]ETH Zürich

High DRAM Power Consumption

Problem: High DRAM (memory) power in today's systems





>40% in POWER7 (Ware+, HPCA'10)

>40% in GPU (Paul+, ISCA'15)

Low-Voltage Memory

- Existing DRAM designs to help reduce DRAM power by lowering supply voltage conservatively
 - Power \propto Voltage²
- DDR3L (low-voltage) reduces voltage from 1.5V to 1.35V (-10%)
- LPDDR4 (low-power) employs low-power I/O interface with I.2V (lower bandwidth)

Can we reduce DRAM power and energy by further reducing supply voltage?

Goals

Understand and characterize the various characteristics of DRAM under reduced voltage

2 Develop a mechanism that reduces DRAM energy by lowering voltage while keeping performance loss within a target

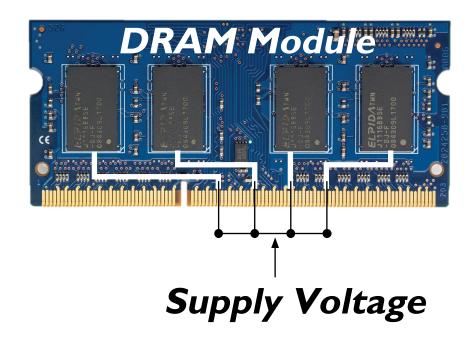
Key Questions

 How does reducing voltage affect reliability (errors)?

 How does reducing voltage affect *DRAM latency*?

 How do we design a new DRAM energy reduction mechanism?

Supply Voltage Control on DRAM



Adjust the *supply voltage* to every chip on the same module

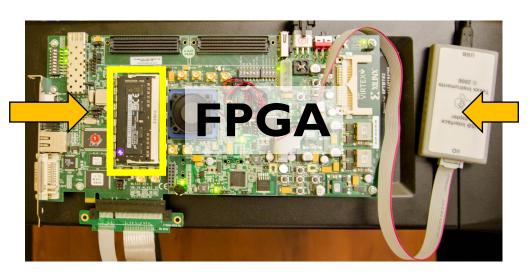
Custom Testing Platform

SoftMC [Hassan+, HPCA'17]: FPGA testing platform to

- I) Adjust supply voltage to DRAM modules
- 2) Schedule DRAM commands to DRAM modules

Existing systems: DRAM commands not exposed to users

DRAM module



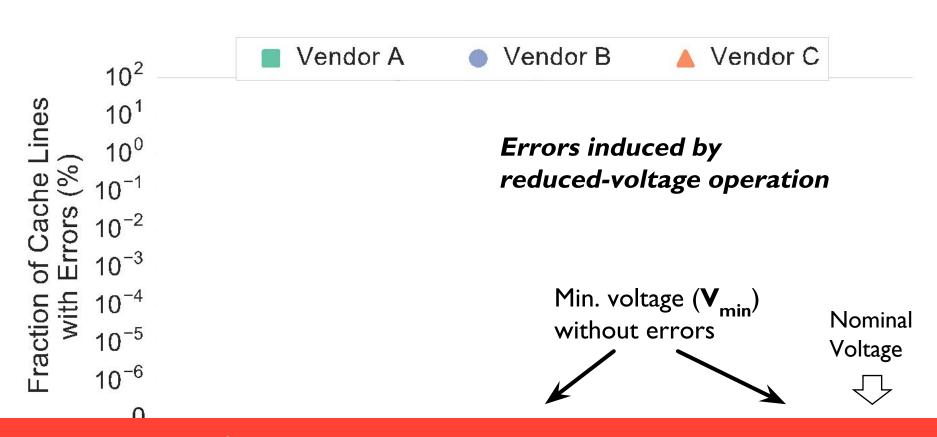
Voltage controller

https://github.com/CMU-SAFARI/DRAM-Voltage-Study

Tested DRAM Modules

- I24 DDR3L (low-voltage) DRAM chips
 - 31 SO-DIMMs
 - I.35V (DDR3 uses I.5V)
 - Density: 4Gb per chip
 - Three major vendors/manufacturers
 - Manufacturing dates: 2014-2016
- Iteratively read every bit in each 4Gb chip under a wide range of supply voltage levels: 1.35V to 1.0V (-26%)

Reliability Worsens with Lower Voltage

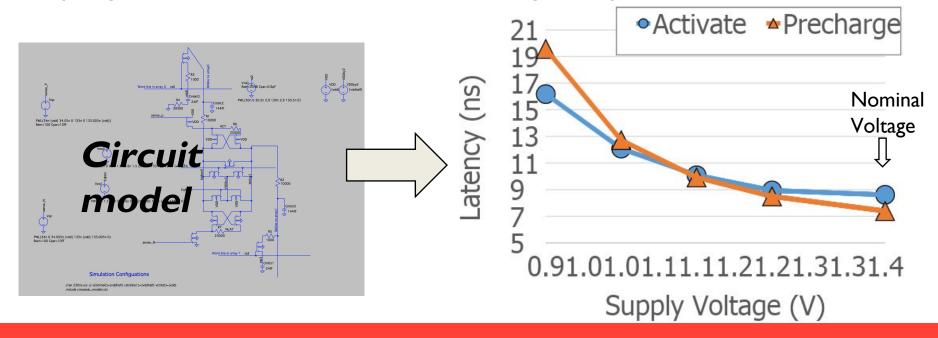


Reducing voltage below V_{min} causes an increasing number of errors

Source of Errors

Detailed circuit simulations (SPICE) of a DRAM cell array to model the behavior of DRAM operations

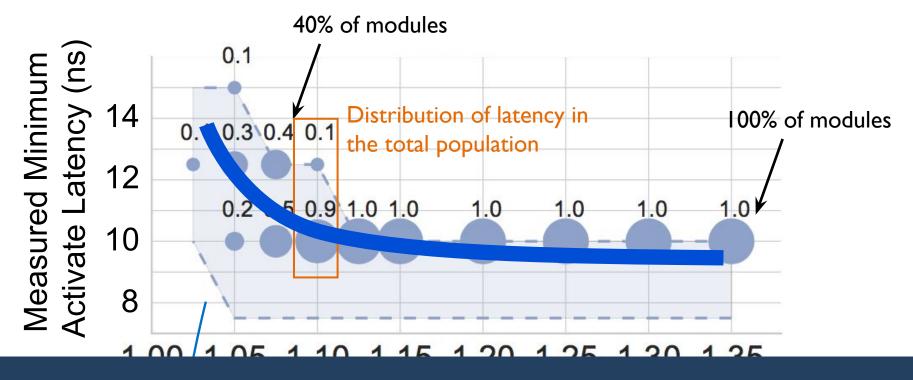
https://github.com/CMU-SAFARI/DRAM-Voltage-Study



Reliable low-voltage operation requires higher latency

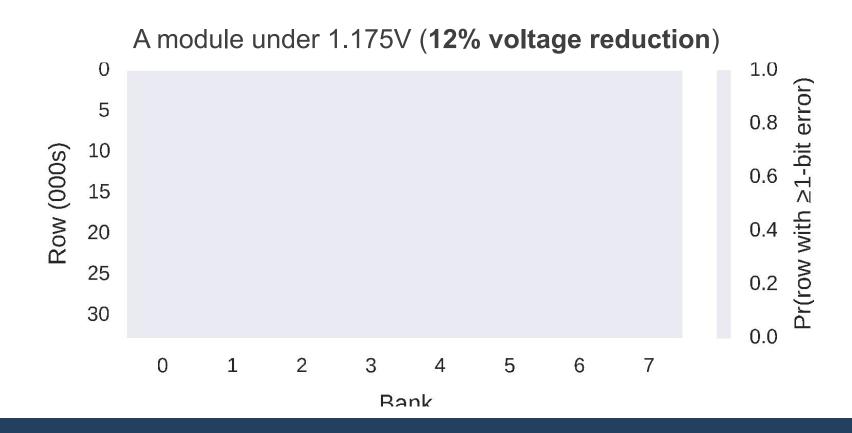
DIMMs Operating at Higher Latency

Measured minimum latency that does not cause errors in DRAM modules



DRAM requires longer latency to access data without errors at lower voltage

Spatial Locality of Errors



Errors concentrate in certain regions

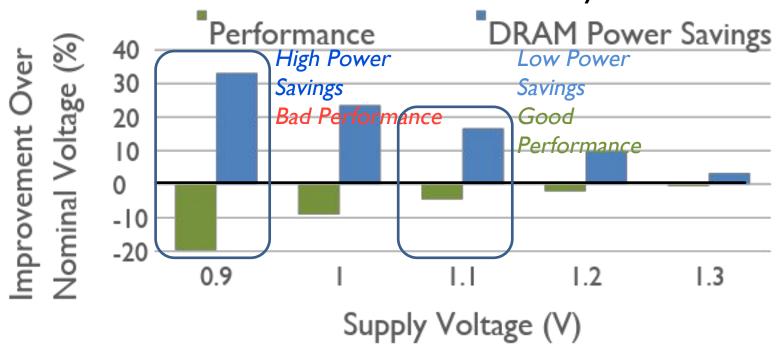
Summary of Key Experimental Observations

- Voltage-induced errors increase as voltage reduces further below V_{\min}
- Errors exhibit spatial locality

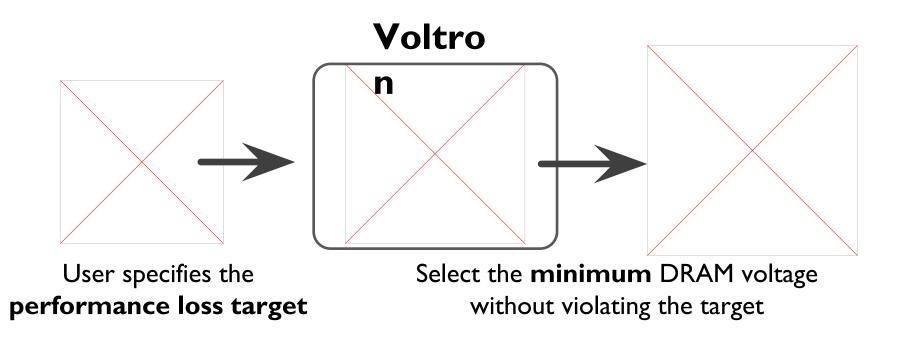
 Increasing the latency of DRAM operations mitigates voltage-induced errors

DRAM Voltage Adjustment to Reduce Energy

- Goal: Exploit the trade-off between voltage and latency to reduce energy consumption
- Approach: Reduce DRAM voltage reliably
 - Performance loss due to increased latency at lower voltage

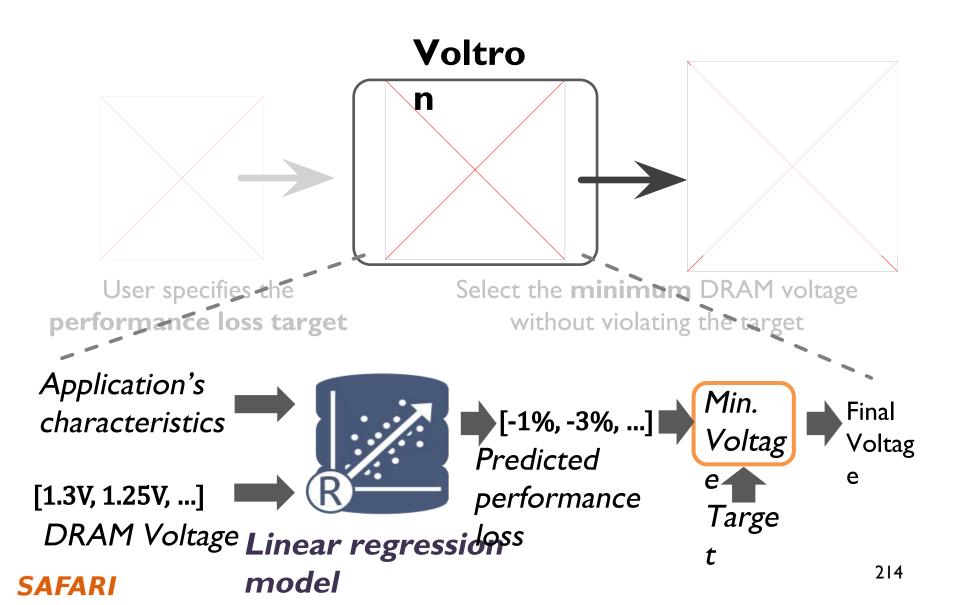


Voltron Overview



How do we predict performance loss due to increased latency under low DRAM voltage?

Linear Model to Predict Performance

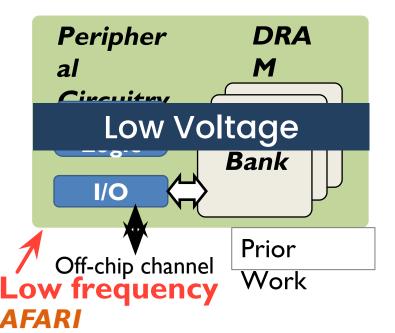


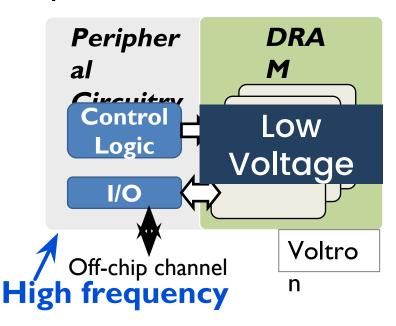
Regression Model to Predict Performance

- Application's characteristics for the model:
 - **Memory intensity**: Frequency of last-level cache misses
 - Memory stall time: Amount of time memory requests stall commit inside CPU
- Handling multiple applications:
 - Predict a performance loss for each application
 - Select the minimum voltage that satisfies the performance target for all applications

Comparison to Prior Work

- <u>Prior work</u>: Dynamically scale *frequency and voltage* of the entire DRAM based on bandwidth demand [David+, ICAC'11]
 - Problem: Lowering voltage on the peripheral circuitry decreases channel frequency (memory data throughput)
- Voltron: Reduce voltage to only DRAM array without changing the voltage to peripheral circuitry

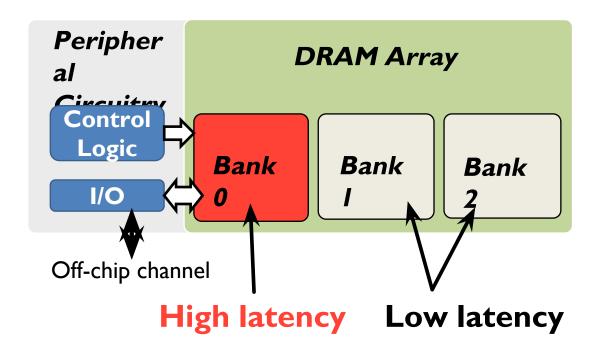




Exploiting Spatial Locality of Errors

Key idea: Increase the latency only for DRAM banks that observe errors under low voltage

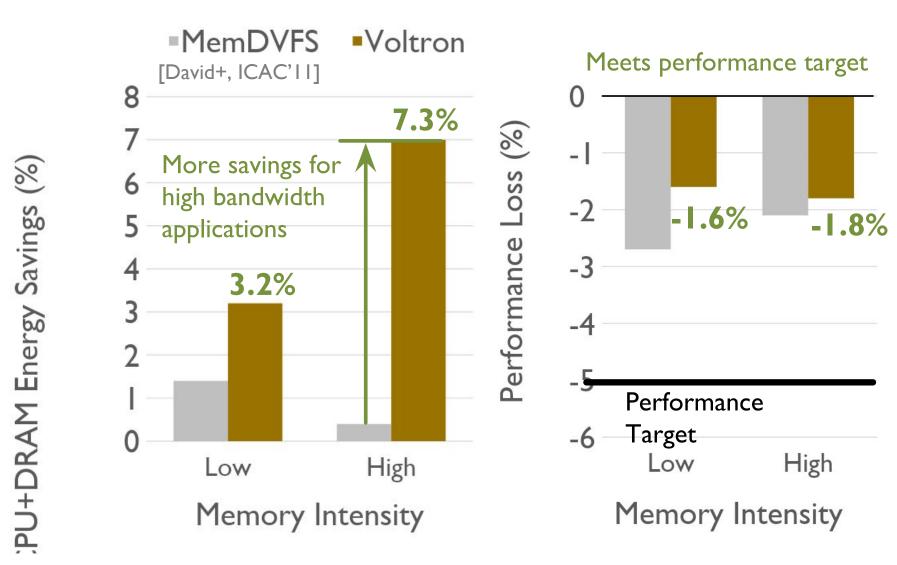
Benefit: Higher performance



Voltron Evaluation Methodology

- Cycle-level simulator: Ramulator [CAL'15]
 - McPAT and DRAMPower for energy measurement
 https://github.com/CMU-SAFARI/ramulator
- **4-core** system with DDR3L memory
- Benchmarks: SPEC2006, YCSB
- Comparison to prior work: **MemDVFS** [David+, ICAC'11]
 - Dynamic DRAM frequency and voltage scaling
 - Scaling based on the memory bandwidth consumption

Energy Savings with Bounded Performance



Voltron: Advantages & Disadvantages

Advantages

- + Can trade-off between voltage and latency to improve energy or performance
 - + Can exploit the high voltage margin present in DRAM

Disadvantages

- Requires finding the reliable operating voltage for each chip □ higher testing cost

Analysis of Latency-Voltage in DRAM Chips

 Kevin Chang, A. Giray Yaglikci, Saugata Ghose, Aditya Agrawal, Niladrish Chatterjee, Abhijith Kashyap, Donghyuk Lee, Mike O'Connor, Hasan Hassan, and <u>u</u>,

"Understanding Reduced-Voltage Operation in Modern DRAM Devices: Experimental Characterization, Analysis, and Mechanisms"

Proceedings of the <u>ACM International Conference on Measurement and Modeling of Computer Systems</u> (**SIGMETRICS**), Urbana-Champaign, IL, USA, June 2017.

Understanding Reduced-Voltage Operation in Modern DRAM Chips: Characterization, Analysis, and Mechanisms

Kevin K. Chang[†] Abdullah Giray Yağlıkçı[†] Saugata Ghose[†] Aditya Agrawal[¶] Niladrish Chatterjee[¶] Abhijith Kashyap[†] Donghyuk Lee[¶] Mike O'Connor^{¶,‡} Hasan Hassan[§] Onur Mutlu^{§,†}

†Carnegie Mellon University [¶]NVIDIA [‡]The University of Texas at Austin [§]ETH Zürich

Reducing Memory Latency to Support Security Primitives

Using Memory for Security

- Generating True Random Numbers (using DRAM)
 - Kim et al., HPCA 2019

- Evaluating Physically Unclonable Functions (using DRAM)
 - Kim et al., HPCA 2018

- Quickly Destroying In-Memory Data (using DRAM)
 - Orosa et al., arxiv 2019

D-RaNGe: Using Commodity DRAM Devices to Generate True Random Numbers with Low Latency and High Throughput

<u>Jeremie S. Kim</u> Minesh Patel Hasan Hassan Lois Orosa Onur Mutlu

HPCA 2019





Carnegie Mellon

D-RaNGe Executive Summary

- Motivation: High-throughput true random numbers enable system security and various randomized algorithms.
 - Many systems (e.g., IoT, mobile, embedded) do not have dedicated True
 Random Number Generator (TRNG) hardware but have DRAM devices
- **Problem**: Current DRAM-based TRNGs either
 - 1. do **not** sample a fundamentally non-deterministic entropy source
 - 2. are **too slow** for continuous high-throughput operation
- <u>Goal</u>: A novel and effective TRNG that uses **existing** commodity DRAM to provide random values with 1) **high-throughput,** 2) **low latency** and 3) no adverse effect on concurrently running applications
- <u>D-RaNGe:</u> Reduce DRAM access latency **below reliable values** and exploit DRAM cells' failure probabilities to generate random values
- Evaluation:
 - 1. Experimentally characterize 282 real LPDDR4 DRAM devices
 - 2. **D-RaNGe** (717.4 Mb/s) has significantly higher throughput (211x)
 - 3. **D-RaNGe (100ns)** has significantly lower latency (**180x**)

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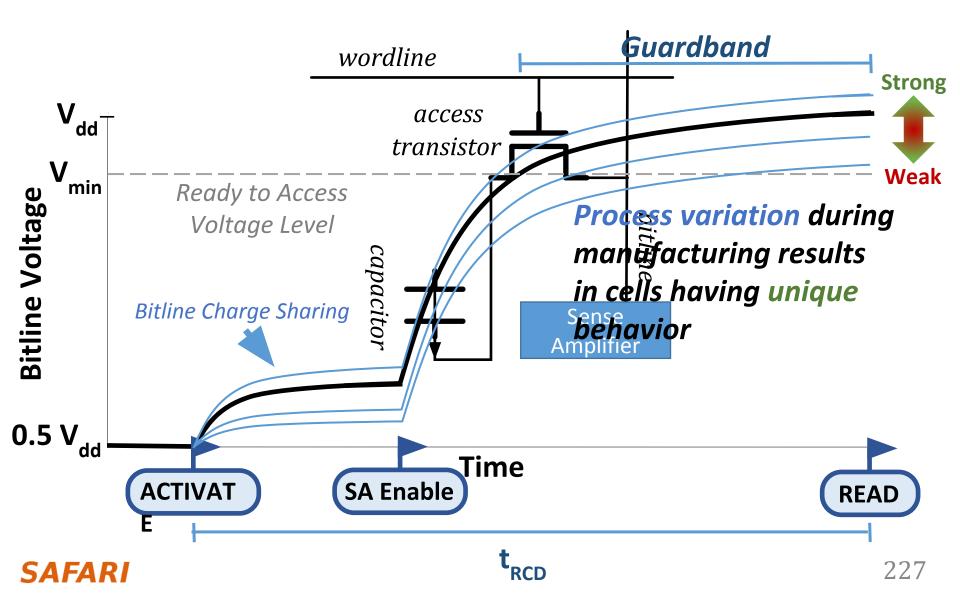
DRAM Latency Characterization of 282 LPDDR4 DRAM Devices

 Latency failures come from accessing DRAM with reduced timing parameters.

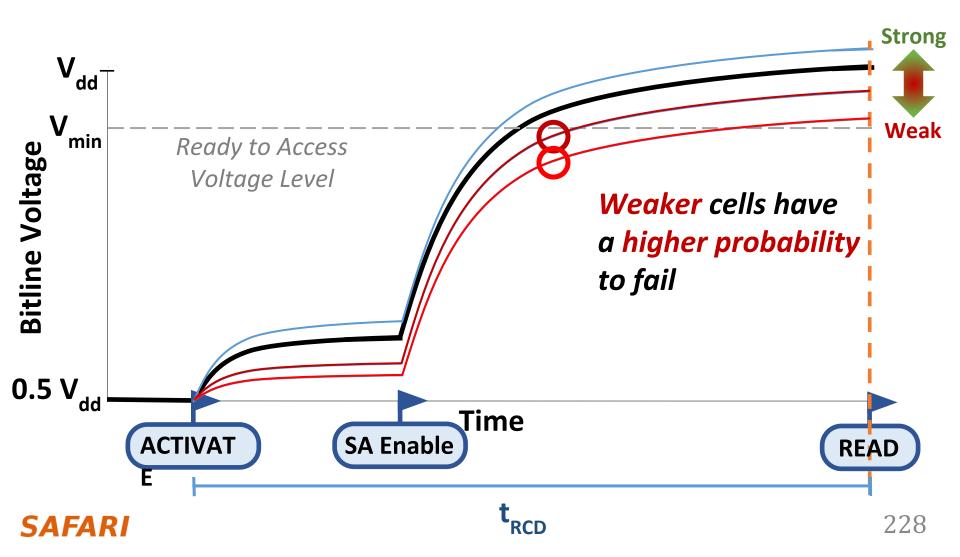
Key Observations:

- 1. A cell's **latency failure** probability is determined by **random process variation**
- 2. Some cells fail randomly

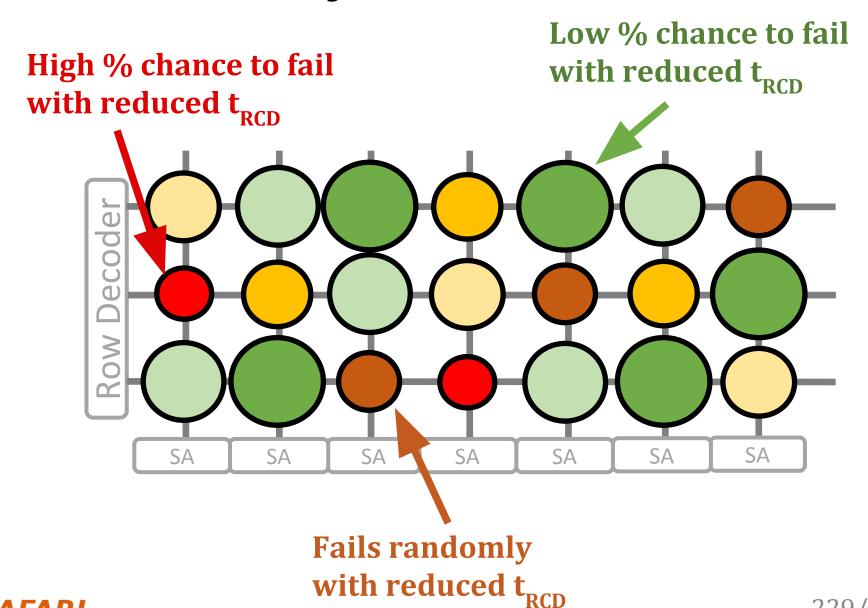
DRAM Accesses and Failures



DRAM Accesses and Failures



D-RaNGe Key Idea

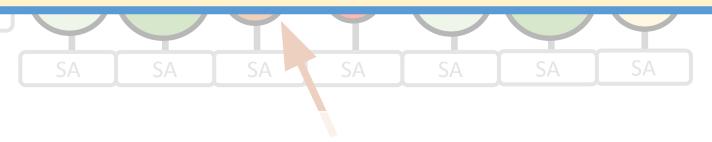


D-RaNGe Key Idea

High % chance to fail with reduced t_{RCD}

Low % chance to fail with reduced t_{RCD}

We refer to cells that fail randomly when accessed with a reduced t_{RCD} as RNG cells



Fails randomly with reduced t_{RC}

Our D-RaNGe Evaluation

- We generate random values by repeatedly accessing RNG cells and aggregating the data read
- The random data satisfies the NIST statistical test suite for randomness
- •The **D-RaNGE** generates random numbers
 - -Throughput: 717.4 Mb/s
 - Latency: 64 bits in <1us
 - **Power**: 4.4 nJ/bit

D-RaNGe: Using Commodity DRAM Devices to Generate True Random Numbers with Low Latency and High Throughput

<u>Jeremie S. Kim</u> Minesh Patel Hasan Hassan Lois Orosa Onur Mutlu

SAFARI

HPCA 2019



Carnegie Mellon

More on D-RaNGe

Jeremie S. Kim, Minesh Patel, Hasan Hassan, Lois Orosa, and Onur Mutlu,
 "D-RaNGe: Using Commodity DRAM Devices to Generate True
 Random Numbers with Low Latency and High Throughput"
 Proceedings of the 25th International Symposium on High-Performance
 Computer Architecture (HPCA), Washington, DC, USA, February 2019.
 [Slides (pptx) (pdf)]
 [Full Talk Video (21 minutes)]

D-RaNGe: Using Commodity DRAM Devices to Generate True Random Numbers with Low Latency and High Throughput

Jeremie S. Kim^{‡§} Minesh Patel[§] Hasan Hassan[§] Lois Orosa[§] Onur Mutlu^{§‡} [‡]Carnegie Mellon University [§]ETH Zürich

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The DRAM Latency PUF:

Quickly Evaluating Physical Unclonable Functions by Exploiting the Latency-Reliability Tradeoff in Modern Commodity DRAM Devices

> <u>Jeremie S. Kim</u> Minesh Patel Hasan Hassan Onur Mutlu









DL-PUF: Executive Summary

Motivation:

- We can authenticate a system via unique signatures if we can evaluate a Physical Unclonable Function (PUF) on it
- Signatures (PUF response) reflect inherent properties of a device
- DRAM is a promising substrate for PUFs because it is widely used
- **Problem**: Current DRAM PUFs are 1) very slow, 2) require a DRAM reboot, or 3) require additional custom hardware
- <u>Goal</u>: To develop a novel and effective PUF for <u>existing</u> commodity DRAM devices with <u>low-latency evaluation time</u> and <u>low system interference</u> across <u>all operating temperatures</u>
- <u>DRAM Latency PUF:</u> Reduce DRAM access latency **below reliable values** and exploit the resulting error patterns as **unique identifiers**

• Evaluation:

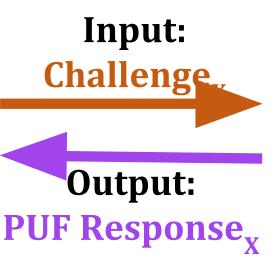
- 1. Experimentally characterize **223 real LPDDR4 DRAM devices**
- 2. **DRAM latency PUF** (88.2 ms) achieves a speedup of **102x/860x** at 70°C/55°C over prior DRAM PUF evaluation mechanisms

Motivation

We want a way to ensure that a system's components are not **compromised**

- Physical Unclonable Function (PUF): a function we evaluate on a device to generate a signature unique to the device
- We refer to the unique signature as a PUF response
- Often used in a Challenge-Response Protocol (CRP)







Motivation

- 1. We want a runtime-accessible PUF
 - Should be evaluated **quickly** with **minimal** impact on concurrent applications
 - Can protect against attacks that swap system components with malicious parts

- **2.** DRAM is a **promising substrate** for evaluating PUFs because it is **ubiquitous** in modern systems
 - Unfortunately, current DRAM PUFs are **slow** and get **exponentially slower** at lower temperatures

DRAM Latency Characterization of 223 LPDDR4 DRAM Devices

•Latency failures come from accessing DRAM with **reduced** timing parameters.

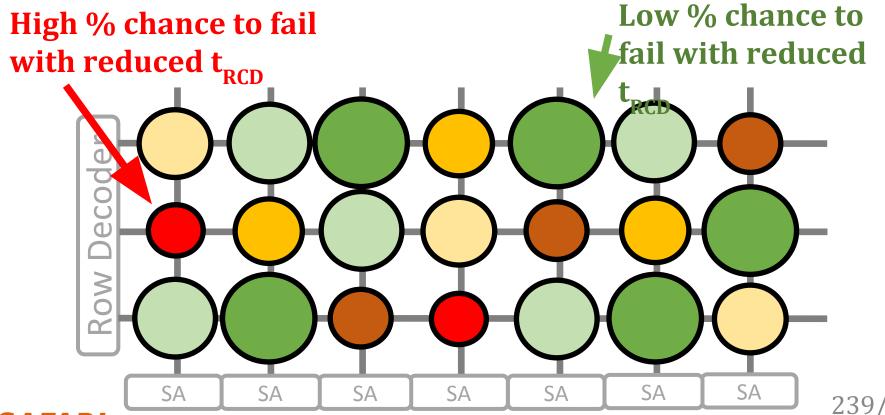
•Key Observations:

- 1. A cell's **latency failure** probability is determined by **random process variation**
- 2. Latency failure patterns are repeatable and unique to a device

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DRAM Latency PUF Key Idea

- · A cell's latency failure probability is inherently related to random process variation from manufacturing
- We can provide repeatable and unique device signatures using latency error patterns

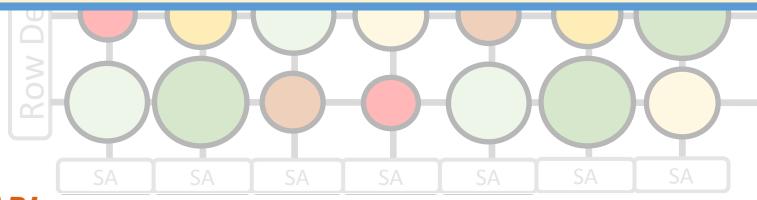


DRAM Latency PUF Key Idea

 A cell's latency failure probability is inherently related to random process variation from manufacturing

· We can provide repeatable and unique device

The key idea is to compose a PUF response using the DRAM cells that fail with high probability



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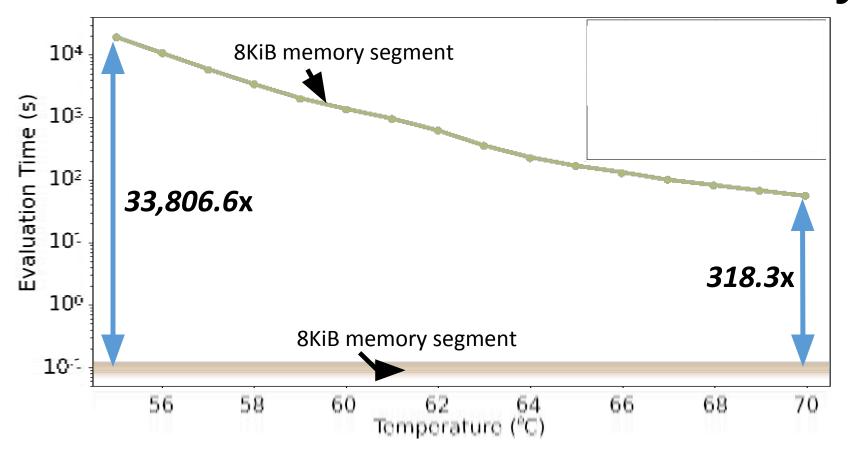
The DRAM Latency PUF Evaluation

•We generate PUF responses using latency errors in a region of DRAM

The latency error patterns satisfy PUF requirements

•The DRAM Latency PUF generates PUF responses in 88.2ms

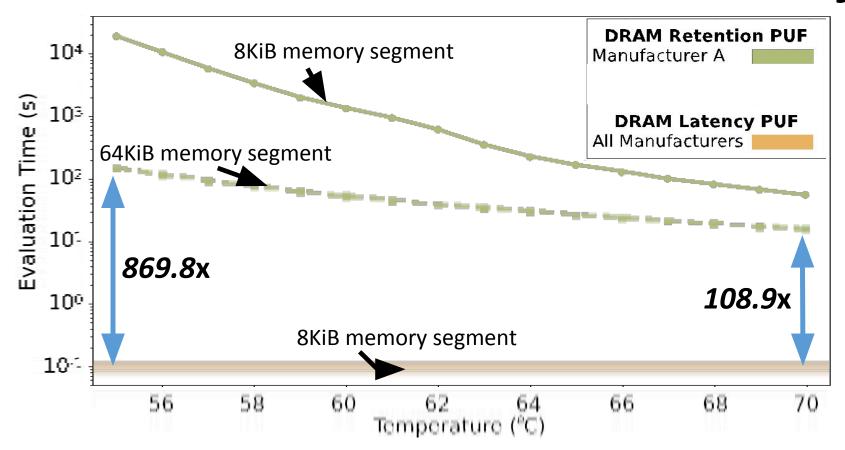
Results – PUF Evaluation Latency



DRAM latency PUF is

1. Fast and constant latency (88.2ms)

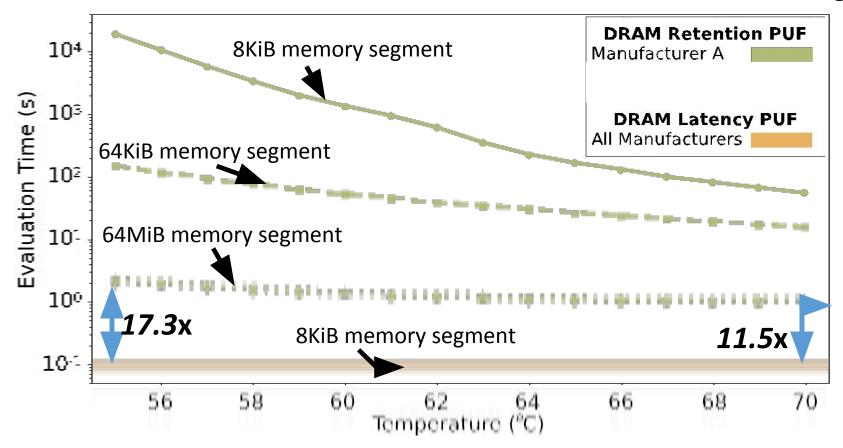
Results - PUF Evaluation Latency



DRAM latency PUF is

1. Fast and constant latency (88.2ms)

Results - PUF Evaluation Latency

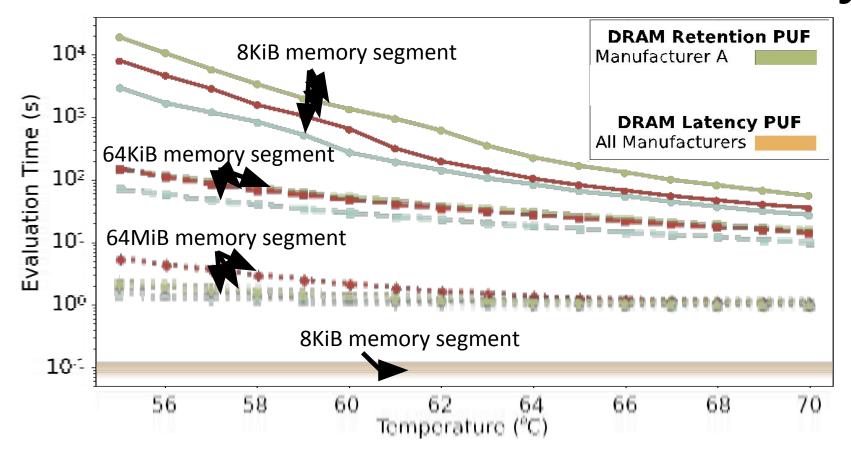


DRAM latency PUF is

1. Fast and constant latency (88.2ms)



Results – PUF Evaluation Latency



DRAM latency PUF is

- 1. Fast and constant latency (88.2ms)
- 2. On average, 102x/860x faster than the previous DRAM PUF with the same DRAM capacity overhead (64KiB)

245/4

Other Results in the Paper

- •How the DRAM latency PUF meets the basic requirements for an effective PUF
- A detailed analysis on:
 - Devices of the three major DRAM manufacturers
 - The evaluation time of a PUF

Further discussion on:

- Optimizing retention PUFs
- System interference of DRAM retention and latency PUFs
- Algorithm to quickly and reliably evaluate DRAM latency PUF
- Design considerations for a DRAM latency PUF
- The DRAM Latency PUF overhead analysis

The DRAM Latency PUF:

Quickly Evaluating Physical Unclonable Functions by Exploiting the Latency-Reliability Tradeoff in Modern Commodity DRAM Devices

<u>Jeremie S. Kim</u> Minesh Patel

Hasan Hassan Onur Mutlu



HPCA 2018



QR Code for the paper

https://people.inf.ethz.ch/omutlu/pub/dram-latency-puf_hpca18.pdf





Carnegie Mellon

DRAM Latency PUFs

Jeremie S. Kim, Minesh Patel, Hasan Hassan, and Onur Mutlu,
 "The DRAM Latency PUF: Quickly Evaluating Physical Unclonable
 Functions by Exploiting the Latency-Reliability Tradeoff in
 Modern DRAM Devices"

Proceedings of the <u>24th International Symposium on High-Performance</u> <u>Computer Architecture</u> (**HPCA**), Vienna, Austria, February 2018. [<u>Lightning Talk Video</u>]

[Slides (pptx) (pdf)] [Lightning Session Slides (pptx) (pdf)]

The DRAM Latency PUF:

Quickly Evaluating Physical Unclonable Functions by Exploiting the Latency-Reliability Tradeoff in Modern Commodity DRAM Devices

Jeremie S. Kim^{†§} Minesh Patel[§] Hasan Hassan[§] Onur Mutlu^{§†}

[†]Carnegie Mellon University [§]ETH Zürich

Reducing Memory Latency by Exploiting Memory Access Patterns

ChargeCache: Executive Summary

 Goal: Reduce average DRAM access latency with no modification to the existing DRAM chips

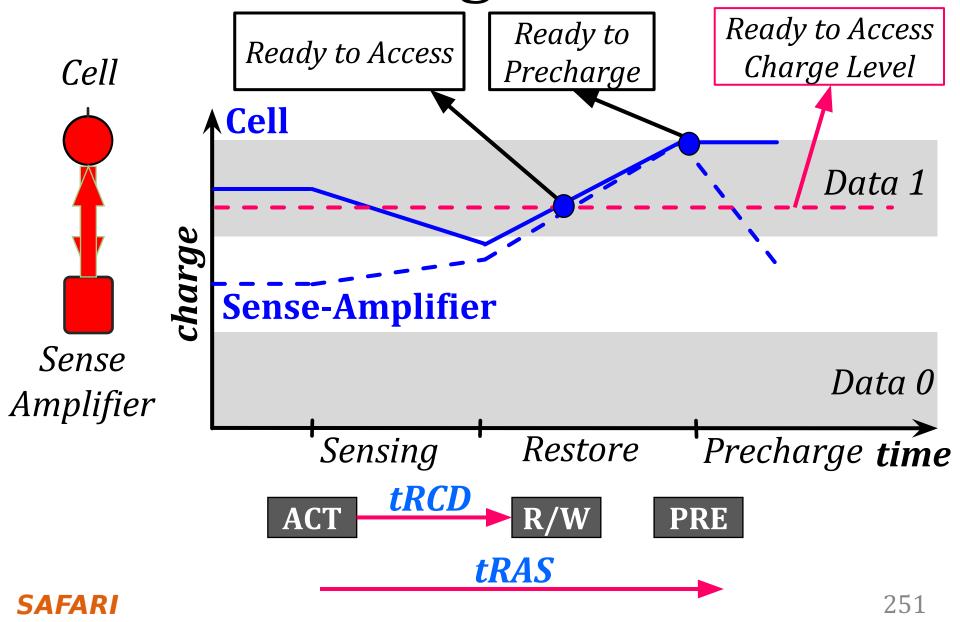
• Observations:

- 1) A highly-charged DRAM row can be accessed with low latency
- 2) A row's charge is restored when the row is accessed
- 3) A recently-accessed row is likely to be accessed again: Row Level Temporal Locality (RLTL)
- **Key Idea**: Track recently-accessed DRAM rows and use lower timing parameters if such rows are accessed again

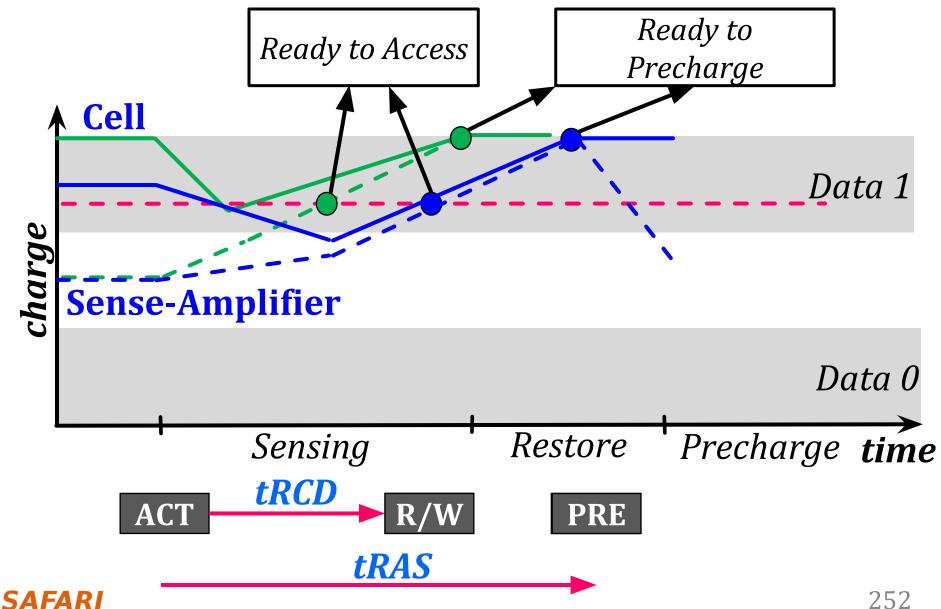
• ChargeCache:

- Low cost & no modifications to the DRAM
- Higher performance (8.6-10.6% on average for 8-core)
- Lower DRAM energy (7.9% on average)

DRAM Charge over Time



Accessing Highly-charged Rows



Observation 1

A highly-charged DRAM row can be accessed with low latency

• tRCD: 44%



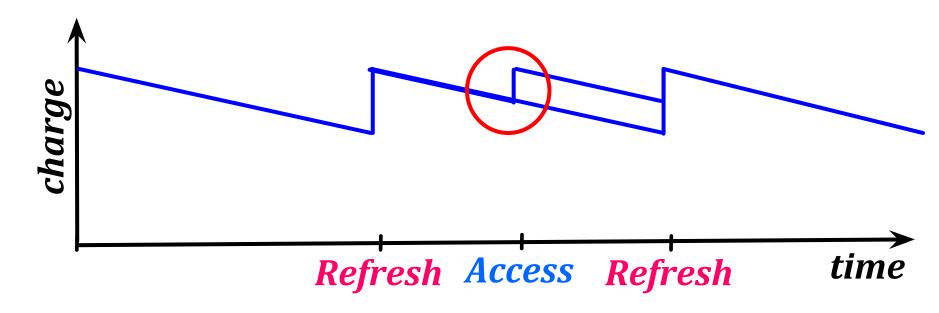
• tRAS: 37%

How does a row become highly-charged?

How Does a Row Become Highly-Charged?

DRAM cells **lose charge** over time Two ways of restoring a row's charge:

- Refresh Operation
- Access



Observation 2

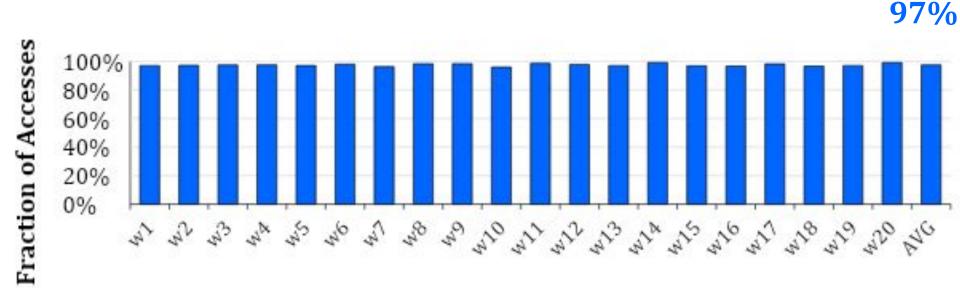
A row's charge is restored when the row is accessed

How likely is a recently-accessed row to be accessed again?

Row Level Temporal Locality (RLTL)

A recently-accessed DRAM row is likely to be accessed again.

• *t*-RLTL: Fraction of rows that are accessed within time *t* after their previous access



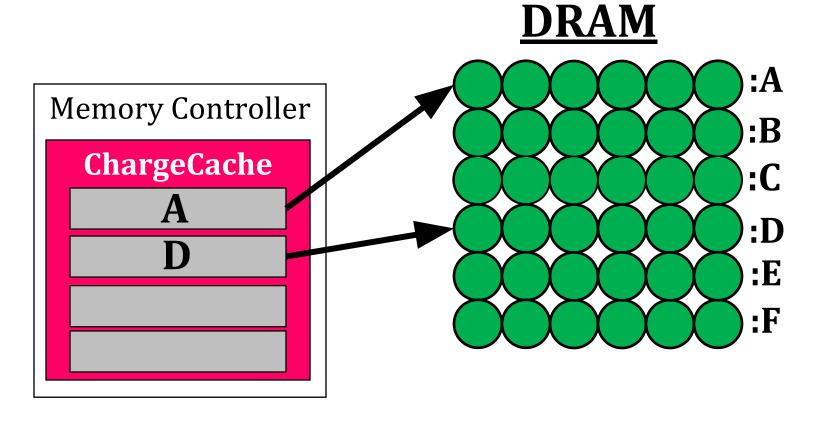
88mss - RUTLIfforseight-core workloads



Key Idea

Track recently-accessed DRAM rows and use lower timing parameters if such rows are accessed again

ChargeCache Overview



Requests: A D A

Change Each be Whits: Use Defauett Timings

Area and Power Overhead

Modeled with CACTI

Area

- − ~5KB for 128-entry ChargeCache
- 0.24% of a 4MB Last Level Cache (LLC) area

Power Consumption

- -0.15 mW on average (static + dynamic)
- -0.23% of the 4MB LLC power consumption

SAFARI

Methodology

Simulator

DRAM Simulator (Ramulator [Kim+, CAL'15])
 https://github.com/CMU-SAFARI/ramulator

Workloads

- 22 single-core workloads
 - SPEC CPU2006, TPC, STREAM
- 20 multi-programmed 8-core workloads
 - By randomly choosing from single-core workloads
- Execute at least 1 billion representative instructions per core (Pinpoints)

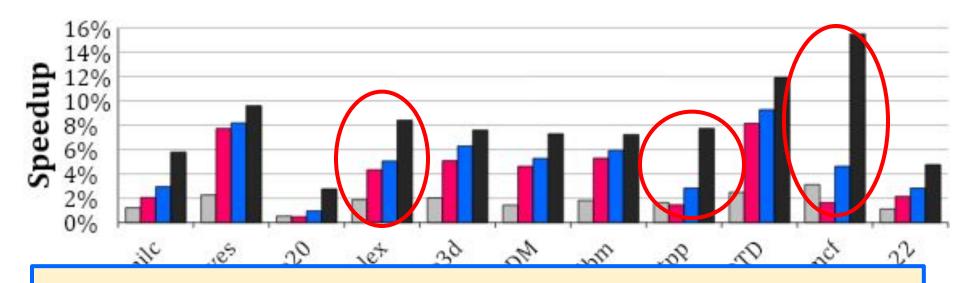
System Parameters

- 1/8 core system with 4MB LLC
- Default tRCD/tRAS of 11/28 cycles

Single-core Performance

NUAT ChargeCache

ChargeCache + NUAT LL-DRAM (Upper bound)



ChargeCache improves single-core performance

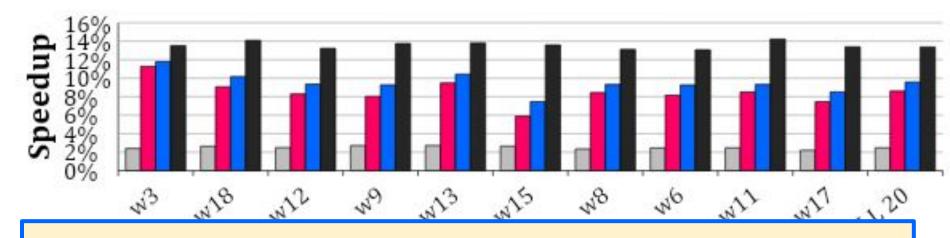
Eight-core Performance

NUAT 2.5%

ChargeCache 9%

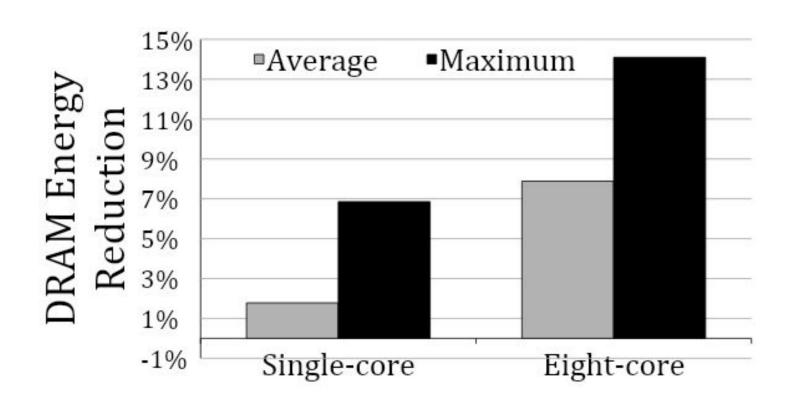
ChargeCache + NUAT

LL-DRAM (Upperbound) 13%



ChargeCache significantly improves multi-core performance

DRAM Energy Savings



ChargeCache reduces DRAM energy

More on ChargeCache

 Hasan Hassan, Gennady Pekhimenko, Nandita Vijaykumar, Vivek Seshadri, Donghyuk Lee, Oguz Ergin, and Onur Mutlu, "ChargeCache: Reducing DRAM Latency by Exploiting Row Access Locality"

Proceedings of the <u>22nd International Symposium on</u>
<u>High-Performance Computer Architecture</u> (**HPCA**), Barcelona, Spain,
March 2016.

[Slides (pptx) (pdf)]
[Source Code]

ChargeCache: Reducing DRAM Latency by Exploiting Row Access Locality

Hasan Hassan^{†*}, Gennady Pekhimenko[†], Nandita Vijaykumar[†] Vivek Seshadri[†], Donghyuk Lee[†], Oguz Ergin^{*}, Onur Mutlu[†]

Partial Restoration of Cell Charge

 Yaohua Wang, Arash Tavakkol, Lois Orosa, Saugata Ghose, Nika Mansouri Ghiasi, Minesh Patel, Jeremie S. Kim, Hasan Hassan, Mohammad Sadrosadati, and Onur Mutlu,

"Reducing DRAM Latency via Charge-Level-Aware Look-Ahead Partial Restoration"

Proceedings of the <u>51st International Symposium on</u> <u>Microarchitecture</u> (**MICRO**), Fukuoka, Japan, October 2018.

Reducing DRAM Latency via Charge-Level-Aware Look-Ahead Partial Restoration

```
Yaohua Wang<sup>†§</sup> Arash Tavakkol<sup>†</sup> Lois Orosa<sup>†*</sup> Saugata Ghose<sup>‡</sup> Nika Mansouri Ghiasi<sup>†</sup> Minesh Patel<sup>†</sup> Jeremie S. Kim<sup>‡†</sup> Hasan Hassan<sup>†</sup> Mohammad Sadrosadati<sup>†</sup> Onur Mutlu<sup>†‡</sup>
```

†ETH Zürich §National University of Defense Technology ‡Carnegie Mellon University *University of Campinas

On DRAM Power Consumption

VAMPIRE DRAM Power Model

Saugata Ghose, A. Giray Yaglikci, Raghav Gupta, Donghyuk Lee, Kais Kudrolli, William X. Liu, Hasan Hassan, Kevin K. Chang, Niladrish Chatterjee, Aditya Agrawal, Mike O'Connor, and Onur Mutlu,

"What Your DRAM Power Models Are Not Telling You: Lessons from a Detailed **Experimental Study**"

Proceedings of the <u>ACM International Conference on Measurement and Modeling of</u> <u>Computer Systems</u> (**SIGMETRICS**), Irvine, CA, USA, June 2018.

[Abstract]

[POMACS Journal Version (same content, different format)]

[Slides (pptx) (pdf)]

VAMPIRE DRAM Power Model

What Your DRAM Power Models Are Not Telling You: Lessons from a Detailed Experimental Study

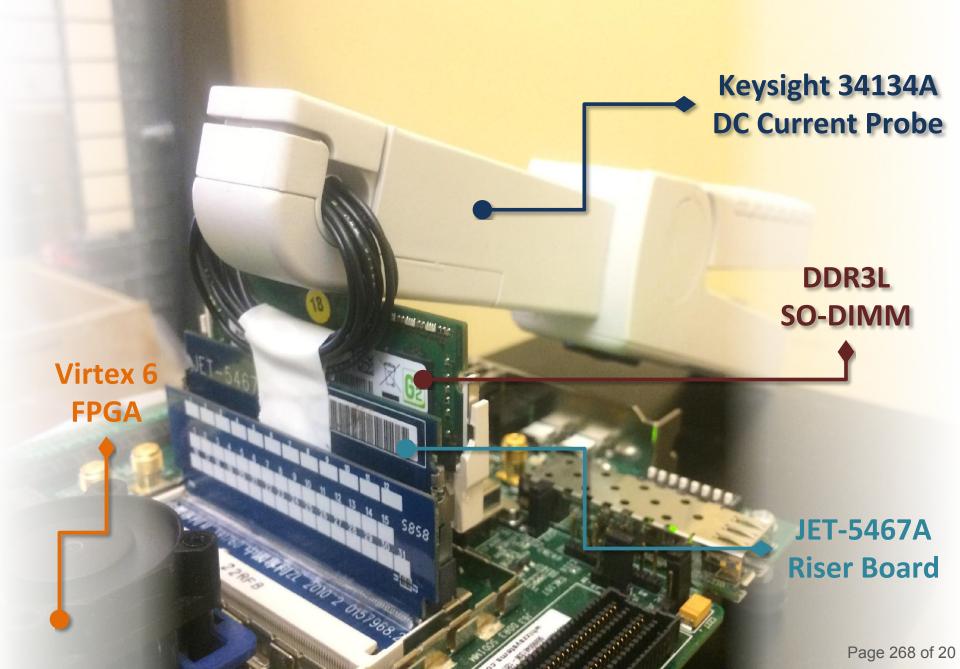
Saugata Ghose[†] Abdullah Giray Yağlıkçı^{‡†} Raghav Gupta[†] Donghyuk Lee[§] Kais Kudrolli[†] William X. Liu[†] Hasan Hassan[‡] Kevin K. Chang[†] Mike O'Connor^{§¶} Onur Mutlu^{‡†} Niladrish Chatterjee[§] Aditya Agrawal[§]

[†]Carnegie Mellon University [‡]ETH Zürich [§]NVIDIA

[¶]University of Texas at Austin

Power Measurement Platform





Power Measurement Methodology

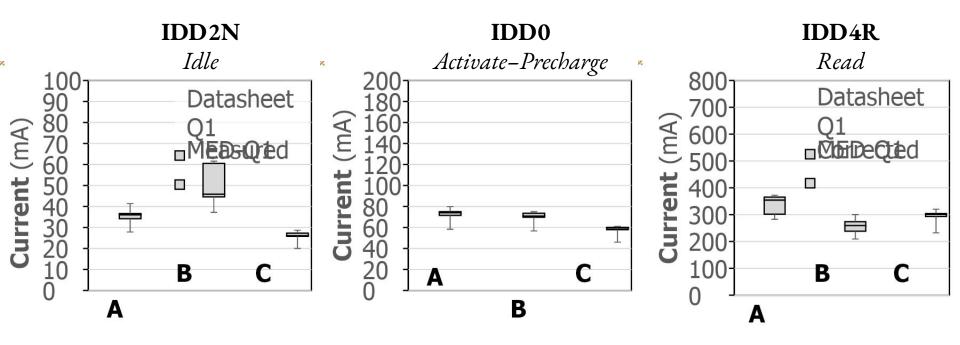


- SoftMC: an FPGA-based memory controller [Hassan+ HPCA '17]
 - Modified to repeatedly loop commands
 - Open-source: https://github.com/CMU-SAFARI/SoftMC
- Measure current consumed by a module during a SoftMC test
- Tested 50 DDR3L DRAM modules (200 DRAM chips)
 - Supply voltage: 1.35 V
 - Three major vendors: A, B, C
 - Manufactured between 2014 and 2016
- For each experimental test that we perform
 - 10 runs of each test per module
 - At least 10 current samples per run

1. Real DRAM Power Varies Widely from IDD





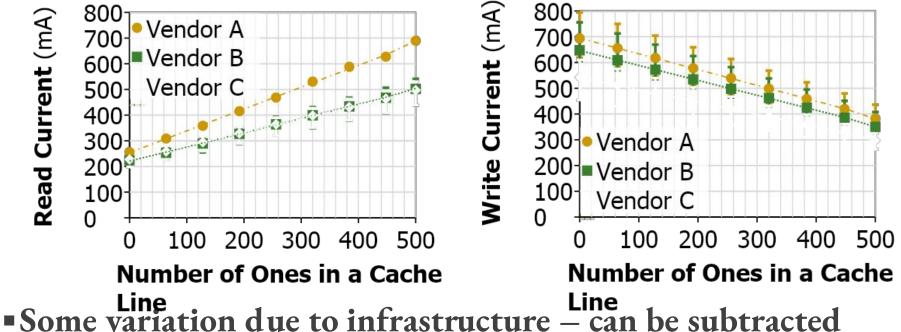


- Different vendors have very different margins (i.e., guardbands)
- Low variance among different modules from same vendor

Current consumed by real DRAM modules varies significantly for all IDD values that we measure

2. DRAM Power is Dependent on Data Values



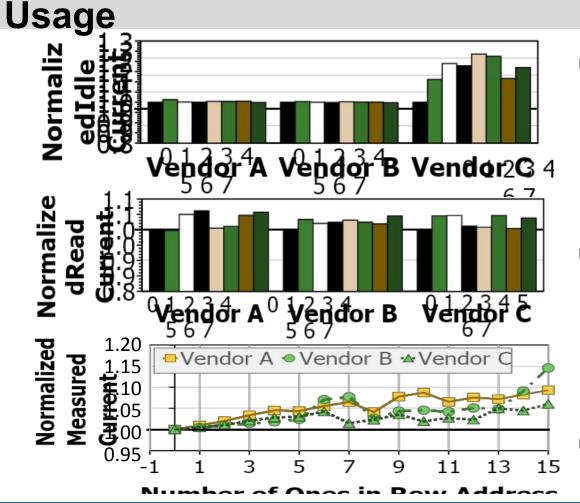


- Without infrastructure variation: up to 230 mA of change
- Toggle affects power consumption, but < 0.15 mA per bit

DRAM power consumption depends strongly on the data value

3. Structural Variation Affects DRAM Power

SAFARI



Vendor C: variation in idle current across banks

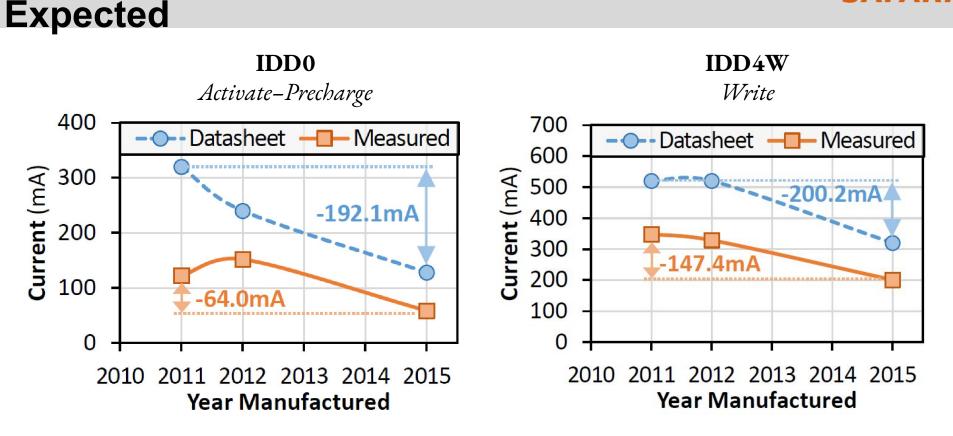
All vendors: variation in read current across banks

 All vendors: variation in activation based on

Significant structural variation: DRAM power varies systematically by bank and row

4. Generational Savings Are Smaller Than





Similar trends for idle and read currents

Actual power savings of newer DRAM is much lower than the savings indicated in the datasheets

Summary of New Observations on DRAM

Power

- 1. Real DRAM modules often consume less power than vendor-provided IDD values state
- 2. DRAM power consumption is dependent on the data value that is read/written
- 3. Across banks and rows, structural variation affects power consumption of DRAM
- 4. Newer DRAM modules save less power than indicated in datasheets by vendors

Detailed observations and analyses in the paper

• VAMPIRE: Variation-Aware model of Memory Power Informed by Real Experiments

Inputs

(from memory system simulator)

Trace of DRAM commands, timing

Data that is being written



Read/Write and Data-Dependent Power Modeling

Idle/Activate/Precharge Power Modeling

Structural Variation Aware Power Modeling

Outputs

Per-vendor power consumption

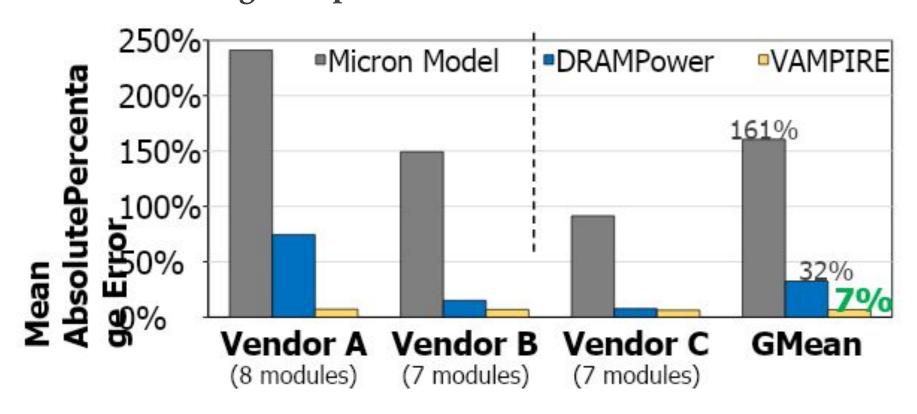
Range for each vendor (optional)

■ VAMPIRE and raw characterization data are open-source: https://github.com/CMU-SAFARI/VAMPIRE

VAMPIRE Has Lower Error Than Existing Models



Validated using new power measurements: details in the



VAMPIRE has very low error for *all* vendors: 6.8% Much more accurate than prior models

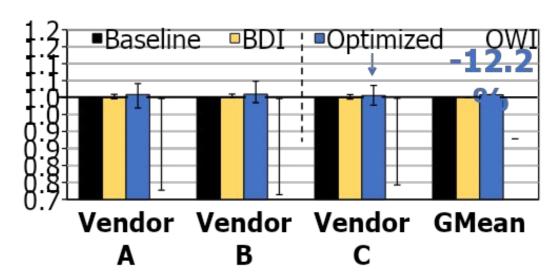
VAMPIRE Enables Several New Studies



- Taking advantage of structural variation to perform variation-aware physical page allocation to reduce power
- Smarter DRAM power-down scheduling
- Reducing DRAM energy with data-dependency-aware

cache line encodings Normalized DRAM Energy

- 23 applications from the SPEC 2006 benchmark suite
- Traces collected using Pin and Ramulator



• We expect there to be many other new studies in the future

VAMPIRE DRAM Power Model

Saugata Ghose, A. Giray Yaglikci, Raghav Gupta, Donghyuk Lee, Kais Kudrolli, William X. Liu, Hasan Hassan, Kevin K. Chang, Niladrish Chatterjee, Aditya Agrawal, Mike O'Connor, and Onur Mutlu,

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[Abstract]

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VAMPIRE DRAM Power Model

What Your DRAM Power Models Are Not Telling You: Lessons from a Detailed Experimental Study

Saugata Ghose[†] Abdullah Giray Yağlıkçı^{‡†} Raghav Gupta[†] Donghyuk Lee[§] Kais Kudrolli[†] William X. Liu[†] Hasan Hassan[‡] Kevin K. Chang[†] Mike O'Connor^{§¶} Onur Mutlu^{‡†} Niladrish Chatterjee[§] Aditya Agrawal[§]

[†]Carnegie Mellon University [‡]ETH Zürich [§]NVIDIA

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